

Plasma Hydrogenation of Carbon Nanotubes

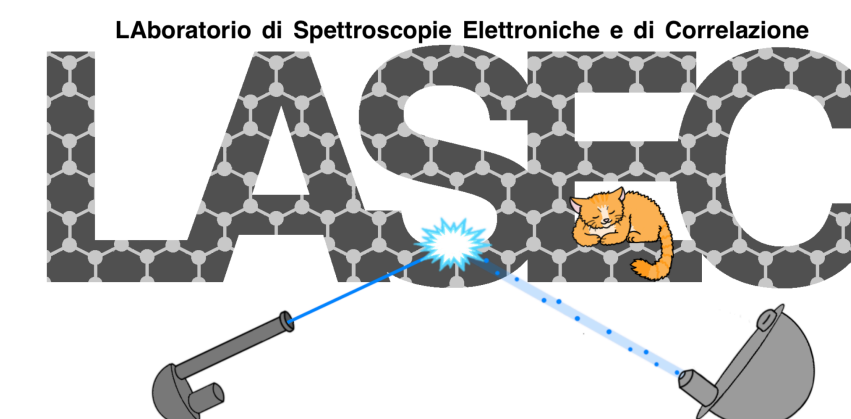
PTOLEMY collaboration meeting Nov 21st 2024

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ANDROMEDA

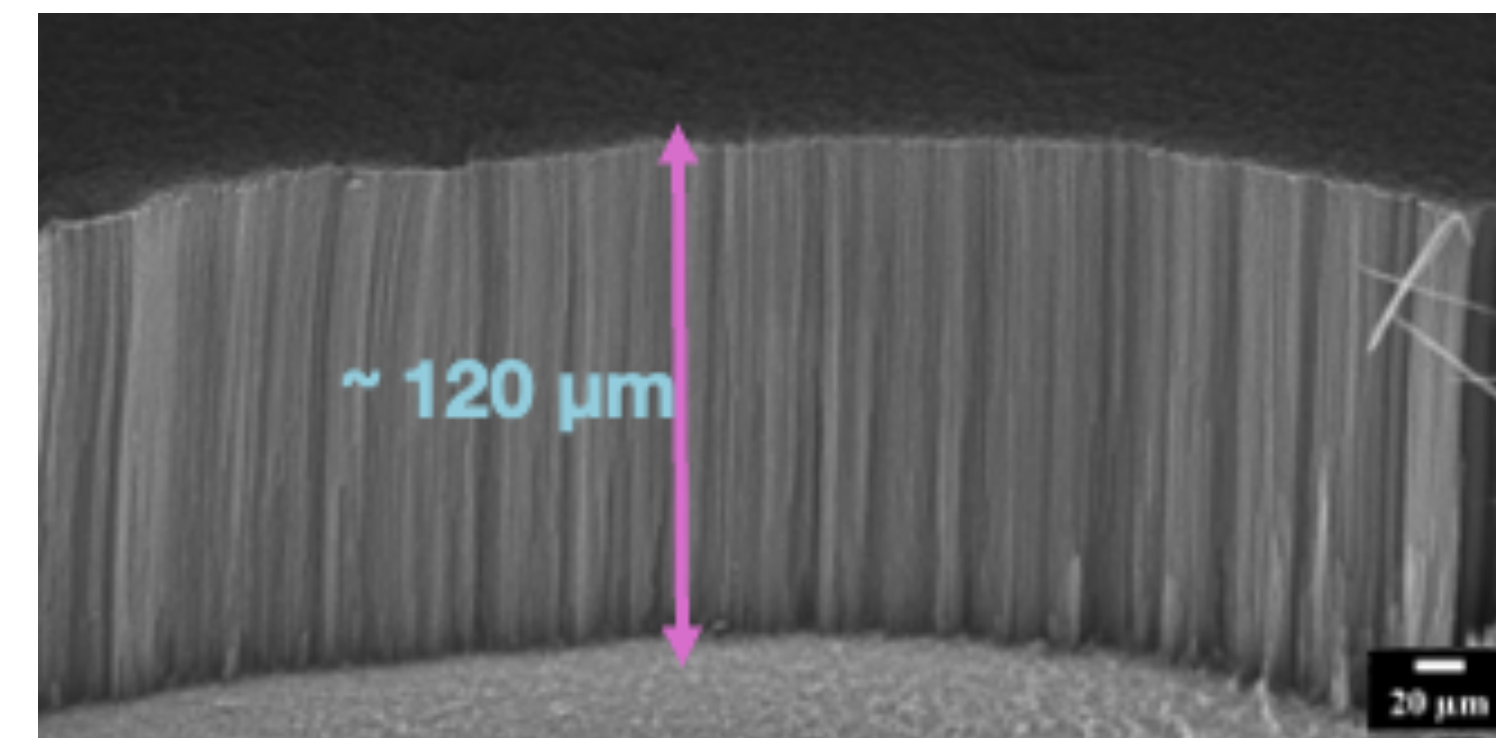
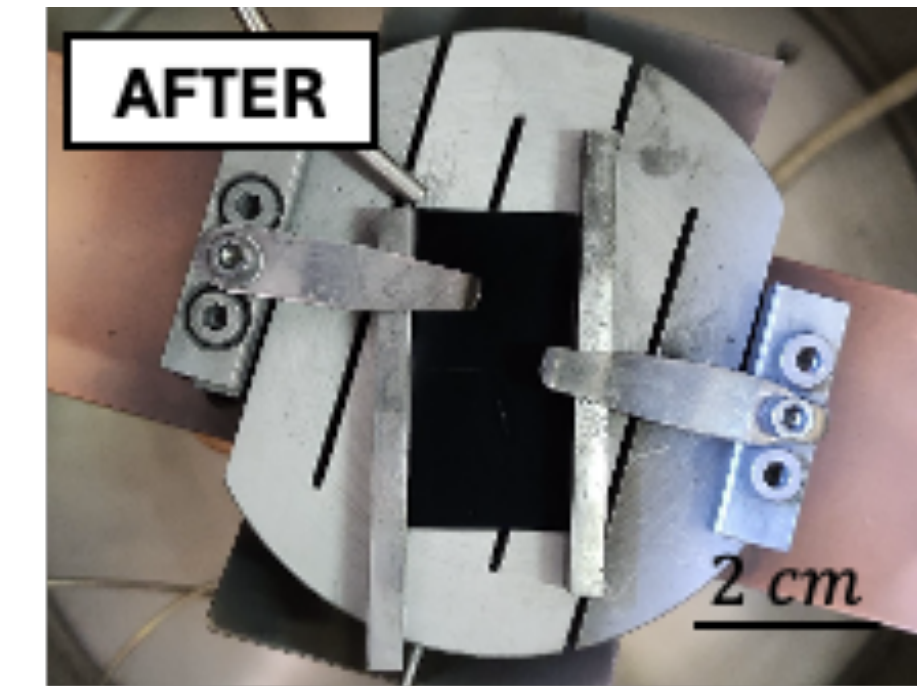
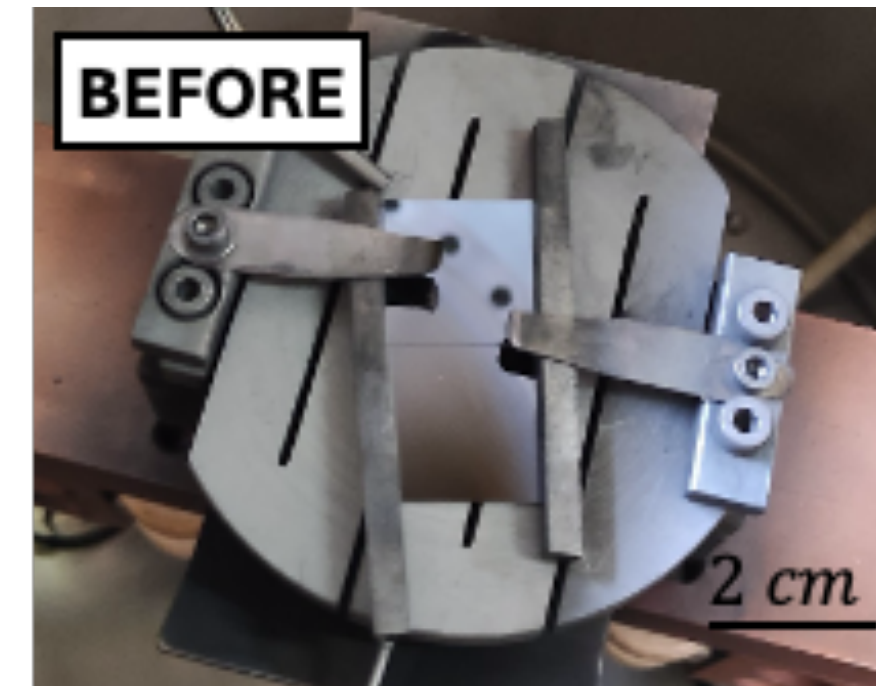
Aligned Nanotube Detector for Research On MeV Darkmatter



Istituto Nazionale di Fisica Nucleare



VACNT growth



Two samples from the same batch
Annealing 650 °C in CVD chamber

CNT pristine

Annealed at ~ 550 °C
Used as a reference

CNT plasma H

Exposed to hydrogen plasma:

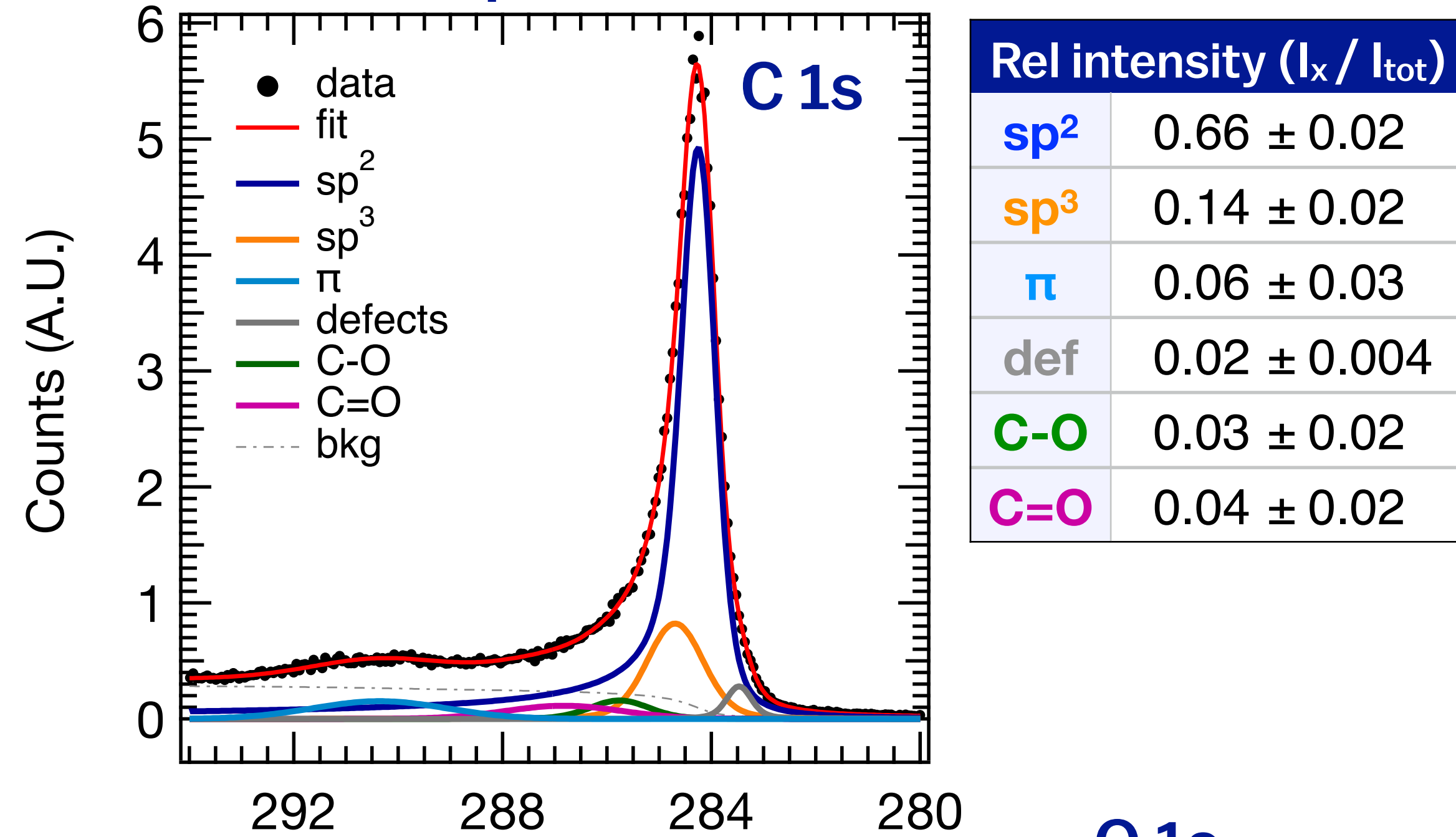
- 100 W
- 0.7 mbar H₂, 300 sccm
- 1 h

Kept in low vacuum during transfer

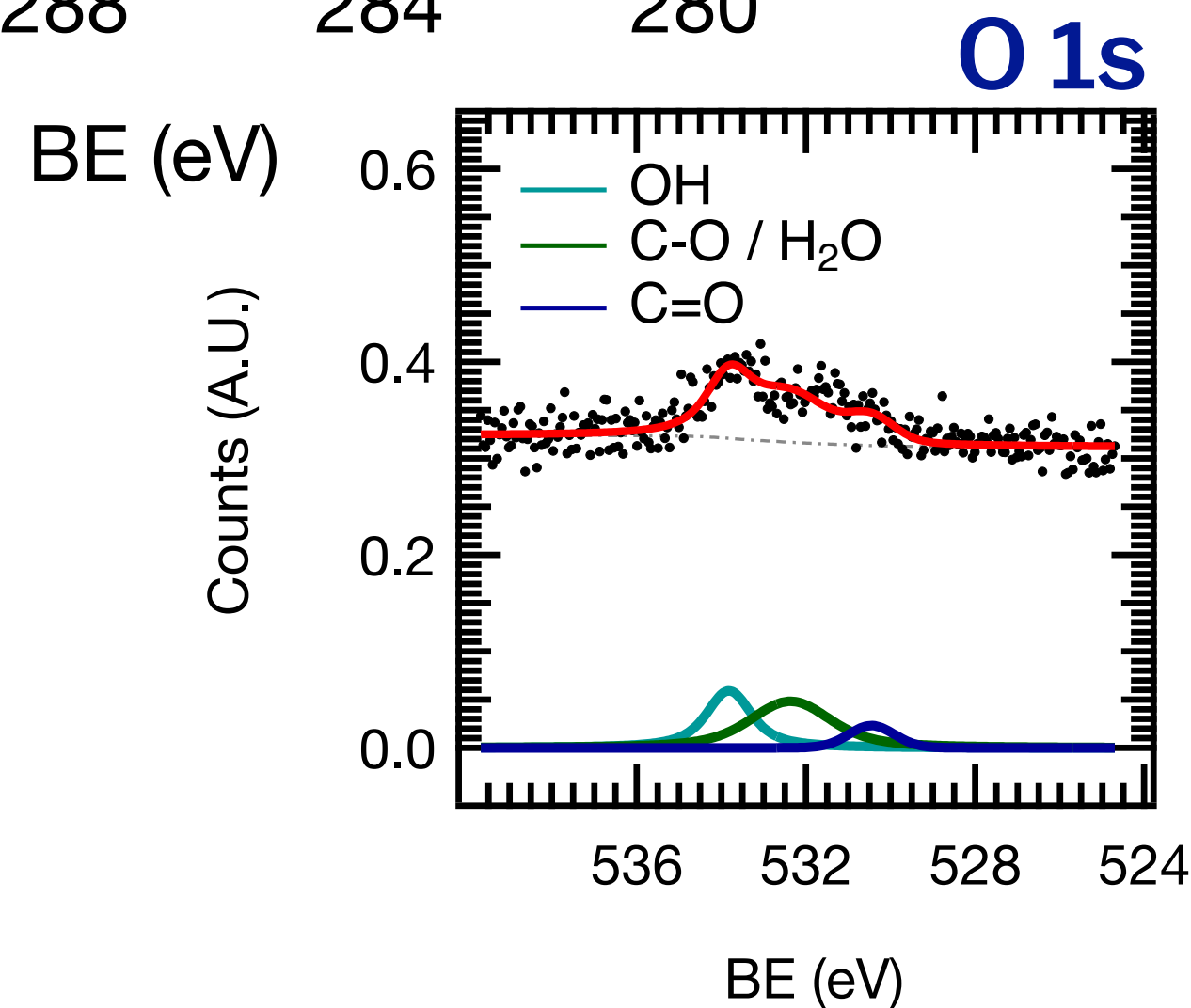
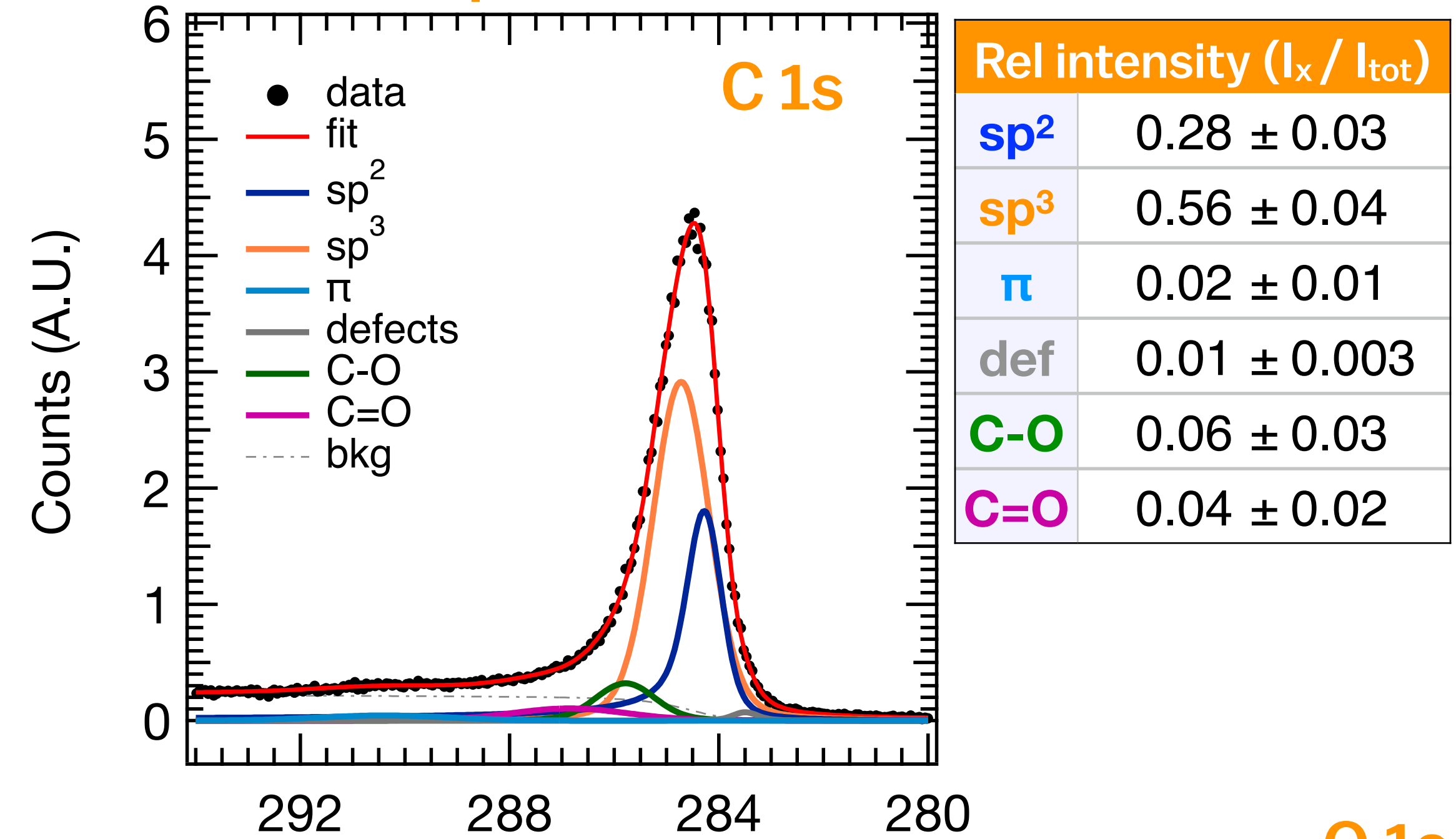
Annealed at ~ 230 °C

XPS analysis: from sp^2 towards sp^3

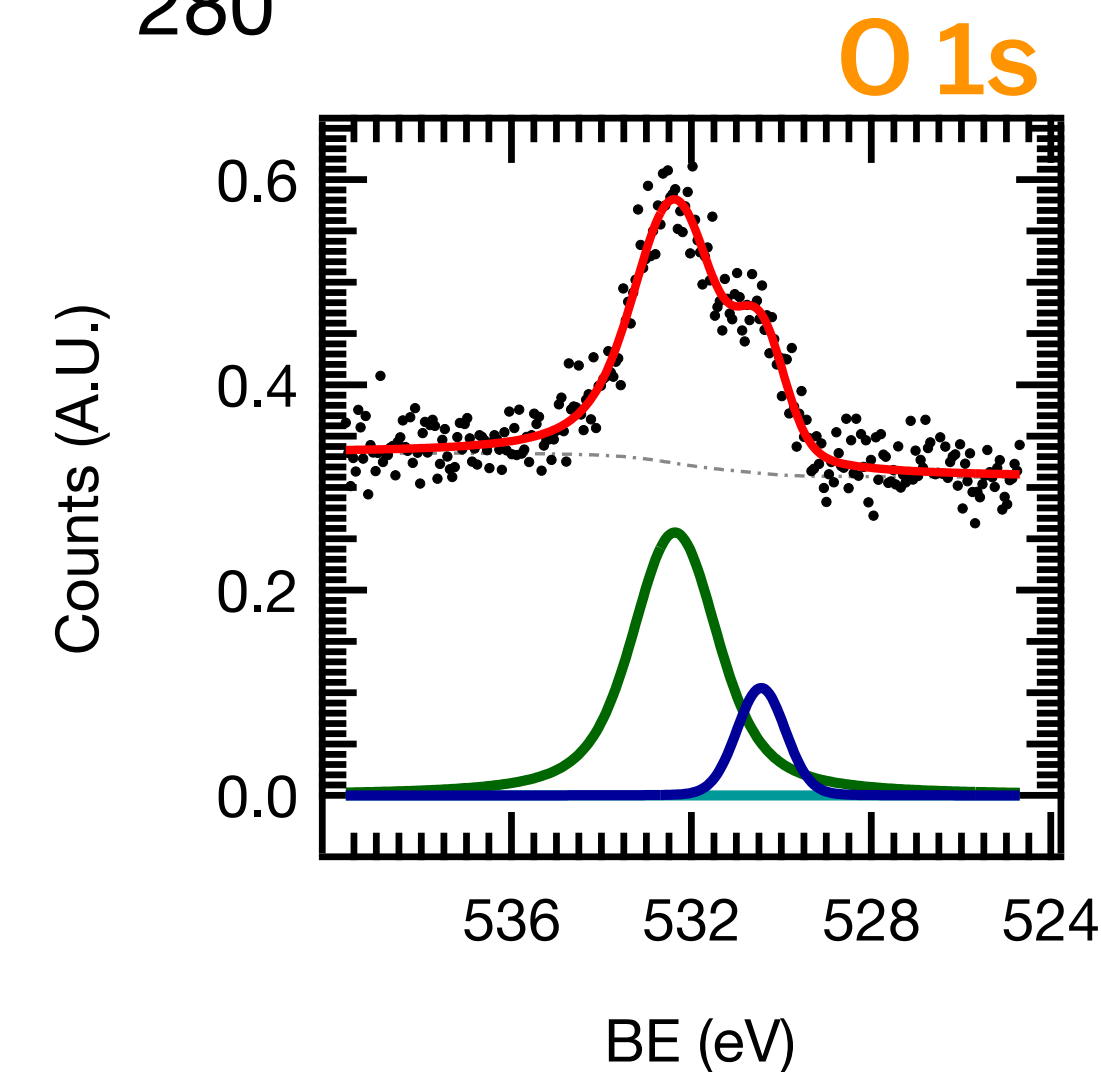
CNT pristine



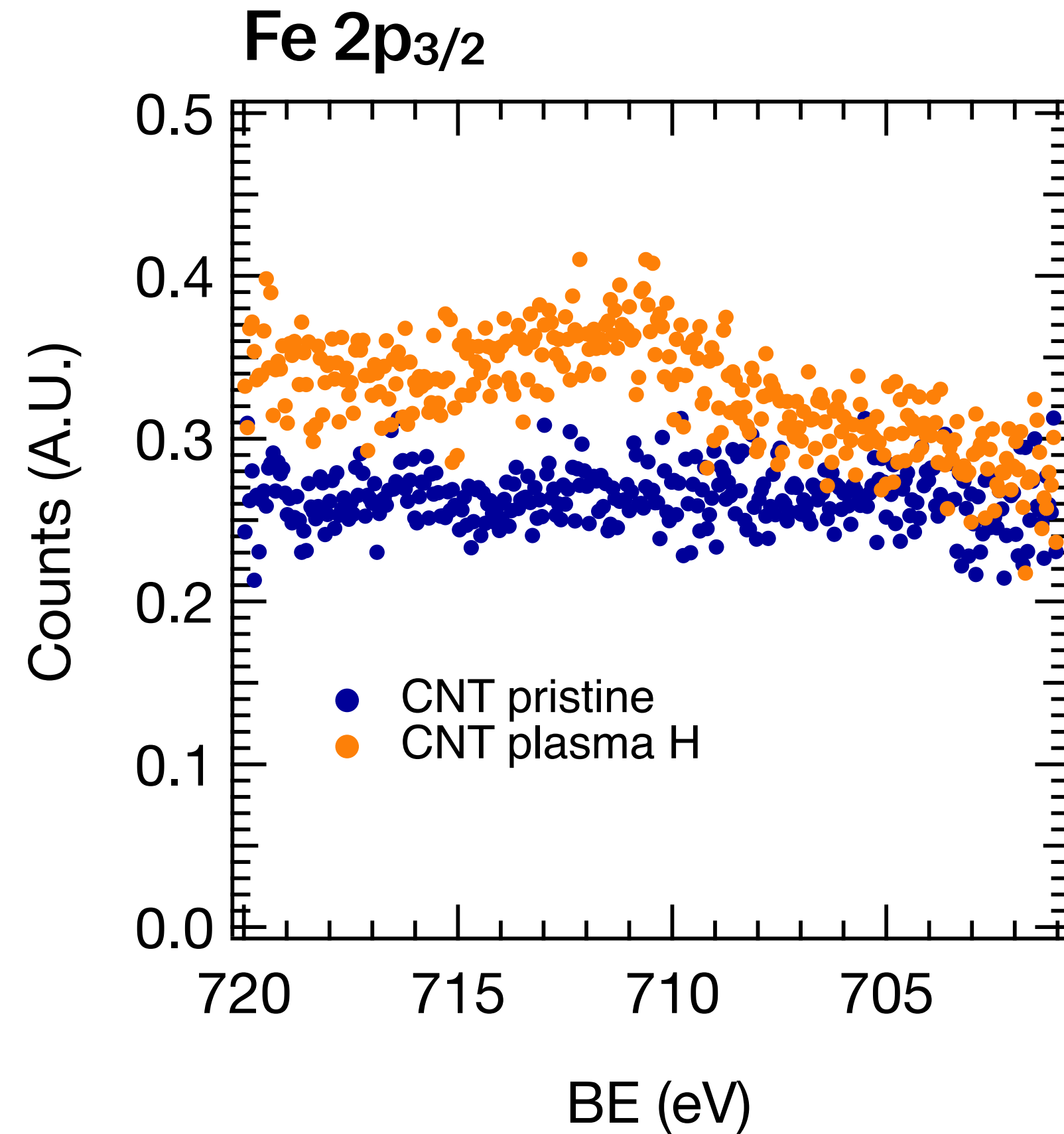
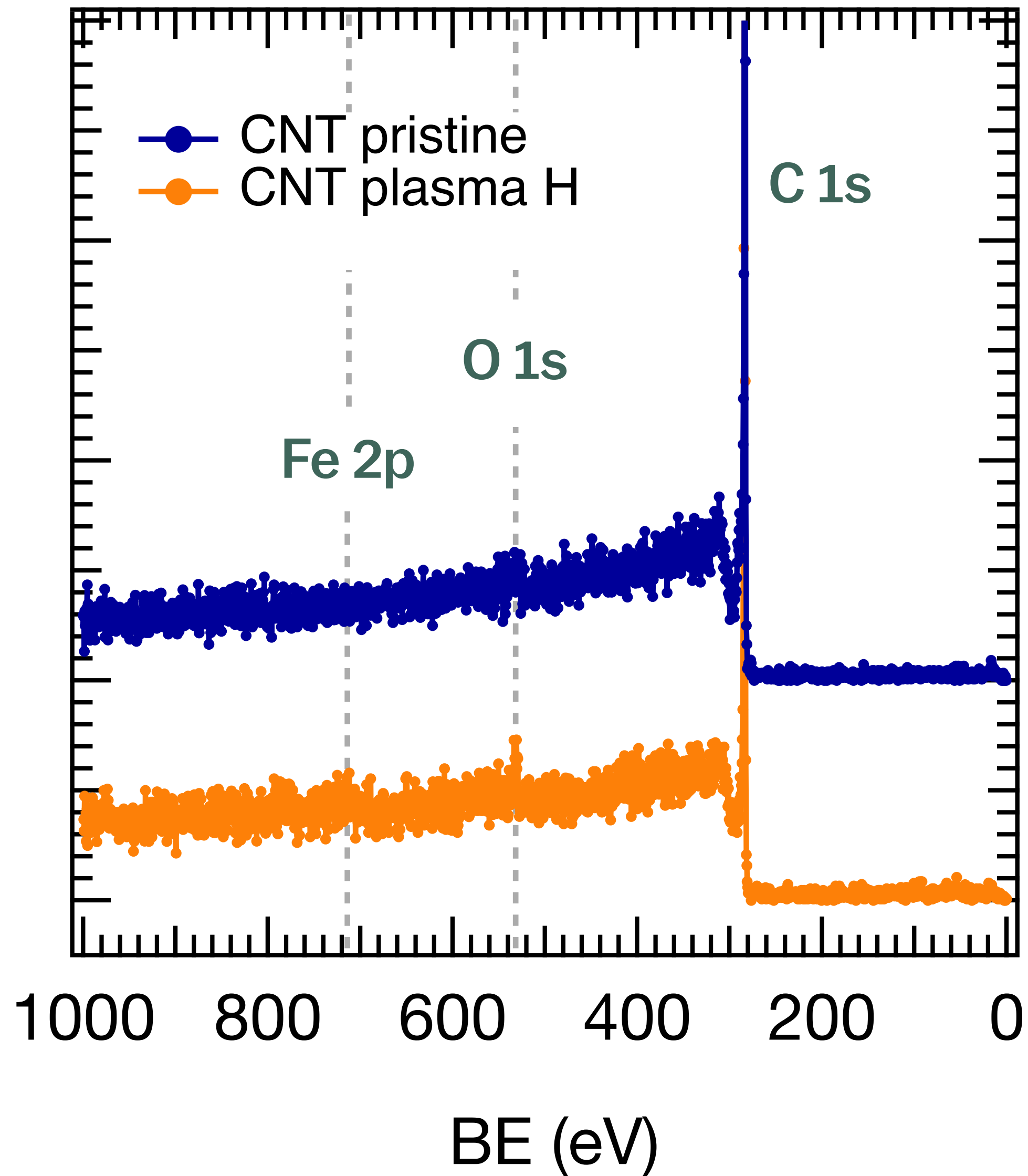
CNT plasma H



○ sp^2 decreases, sp^3 increases (x4)
 ○ C-O and C=O increases



XPS Survey Scan Reveals Iron Traces in Hydrogenated CNTs

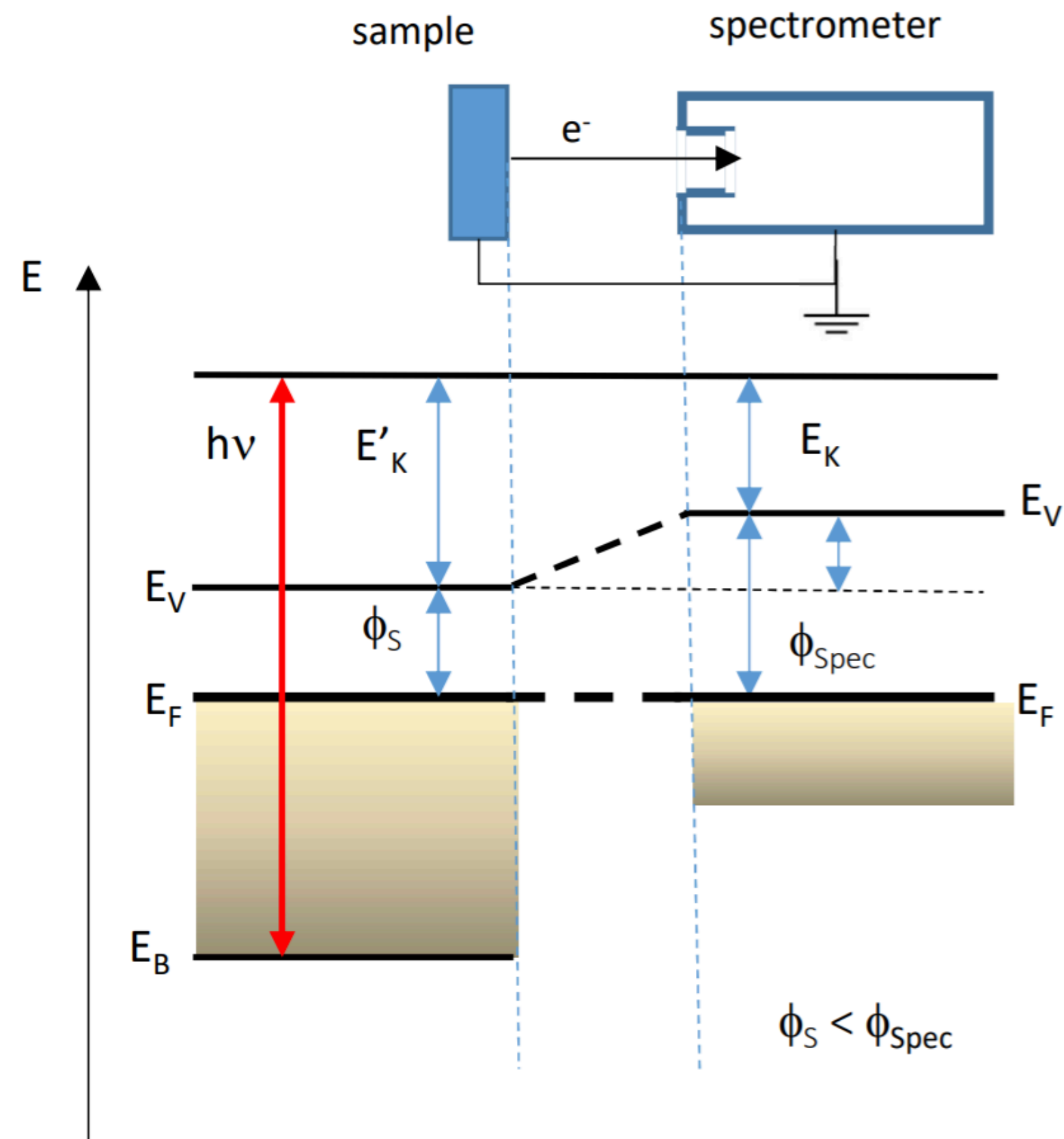


Why a higher Fe 2p intensity in hydrogenated CNT?

It may require SEM investigation



How to measure a Work Function



Analyzer point of view

$$E_K^{min} = \phi_S - \phi_{Spec}$$

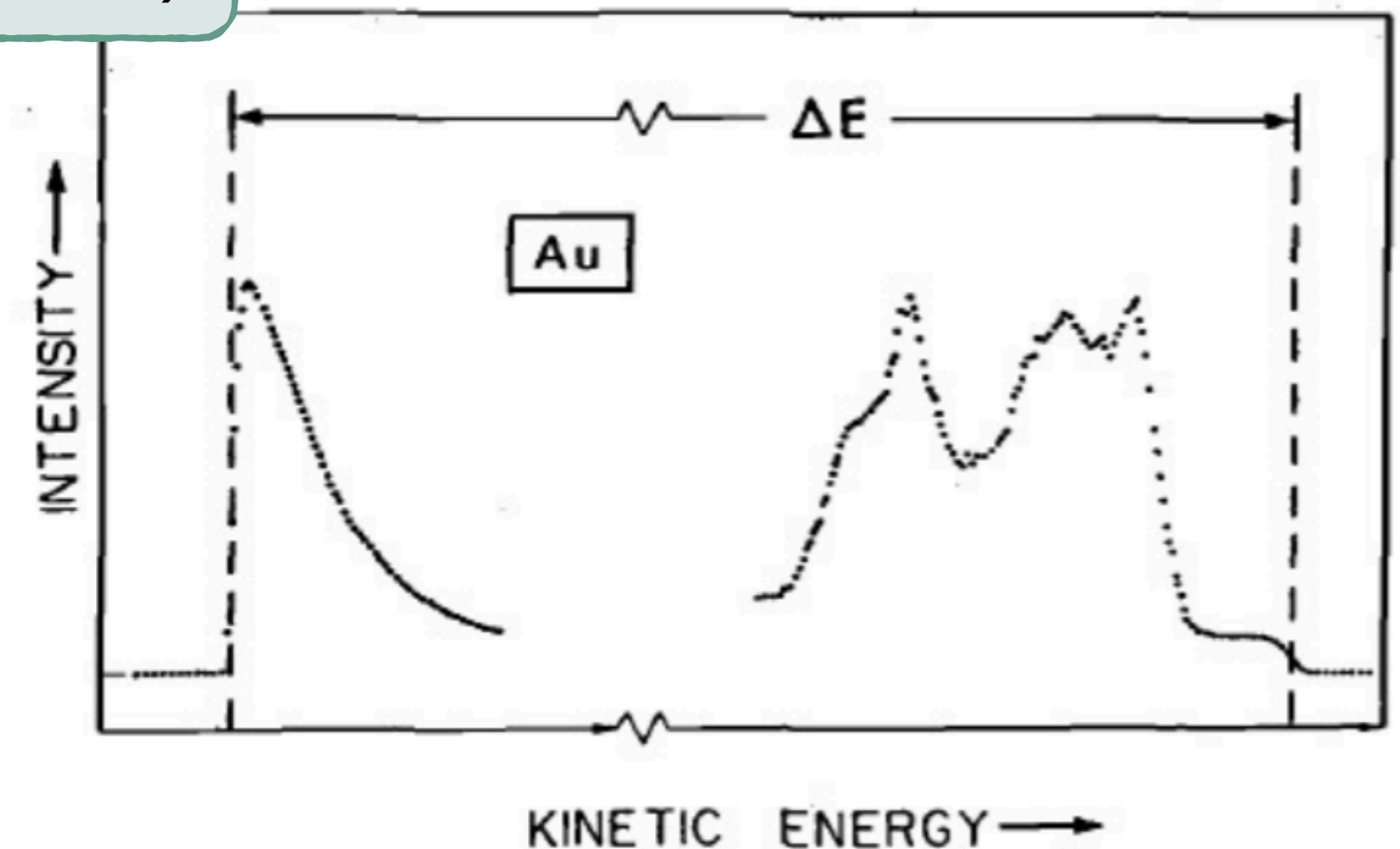
$$E_K^{max} = h\nu - \phi_{Spec}$$

ΔE_K depends only on the sample

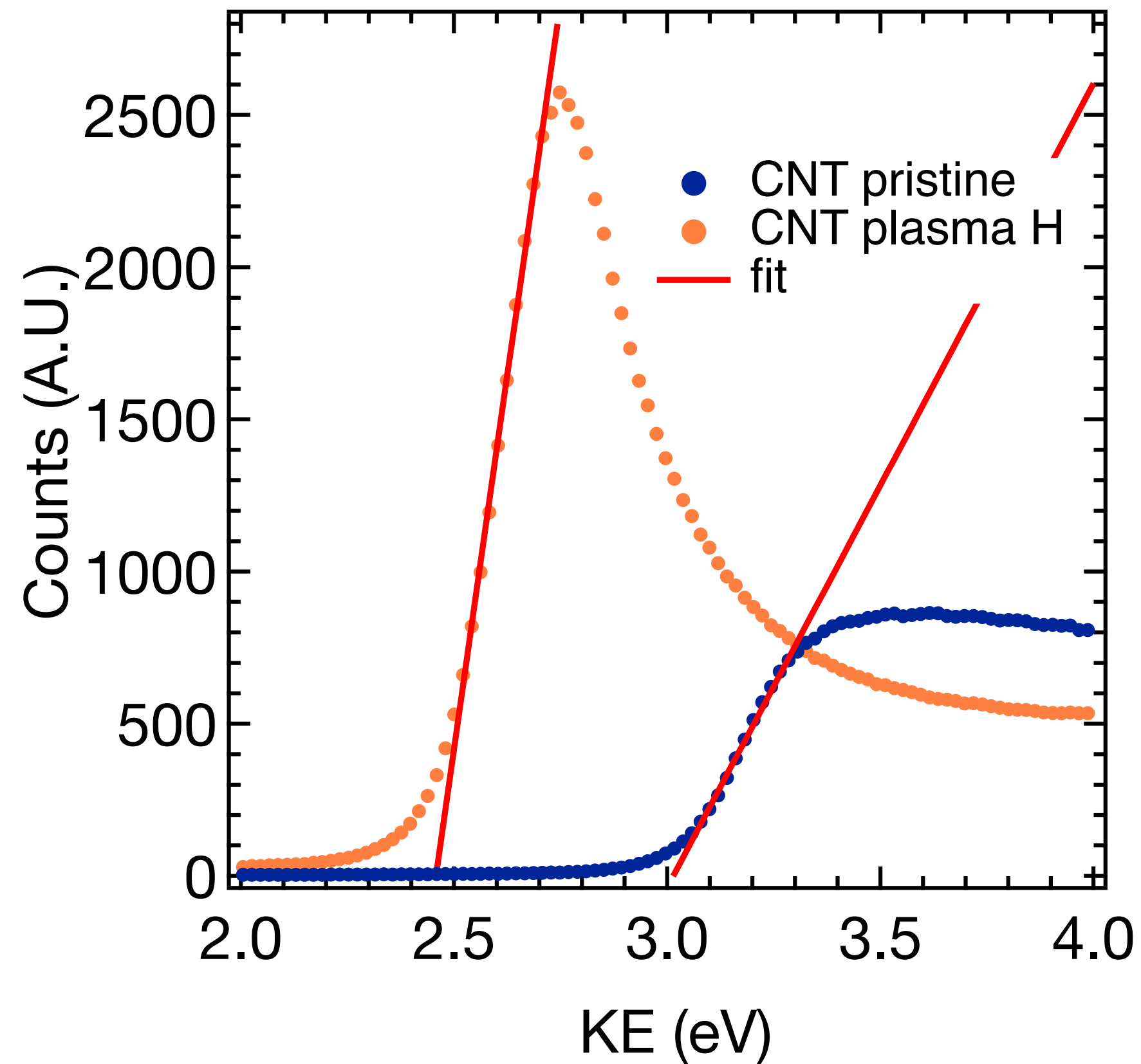
$$\Delta E_K = E_K^{max} - E_K^{min} = h\nu - \phi_S$$

$$\phi_{sample} = h\nu - \Delta E_K = h\nu - (FL - SE)$$

Bias voltage applied to the sample to measure the secondary electron onset



Secondary Electron onset (SE)



Work Function measure:

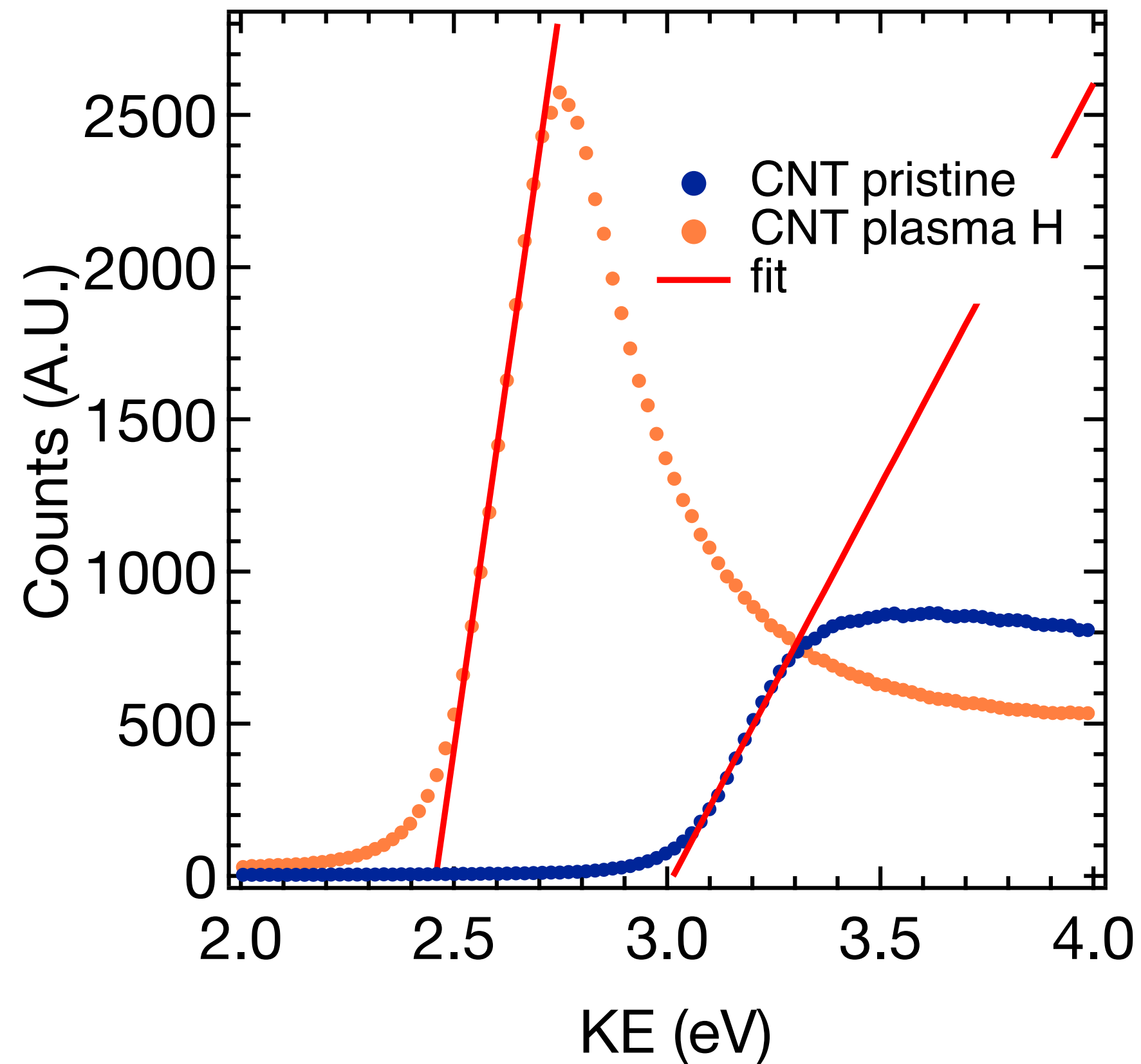
$$\phi_{\text{sample}} = h\nu - \Delta E_k = h\nu - (\text{FL} - \text{SE})$$

Surface dipole changes:

- **WF lowers** from 4.33 ± 0.05 eV to 3.81 ± 0.05 eV

$V_{\text{BIAS}} = -3$ V

Secondary Electron onset (SE)



$V_{BIAS} = -3 V$

Work Function measure:

$$\phi_{sample} = h\nu - \Delta E_k = h\nu - (FL - SE)$$

Surface dipole changes:

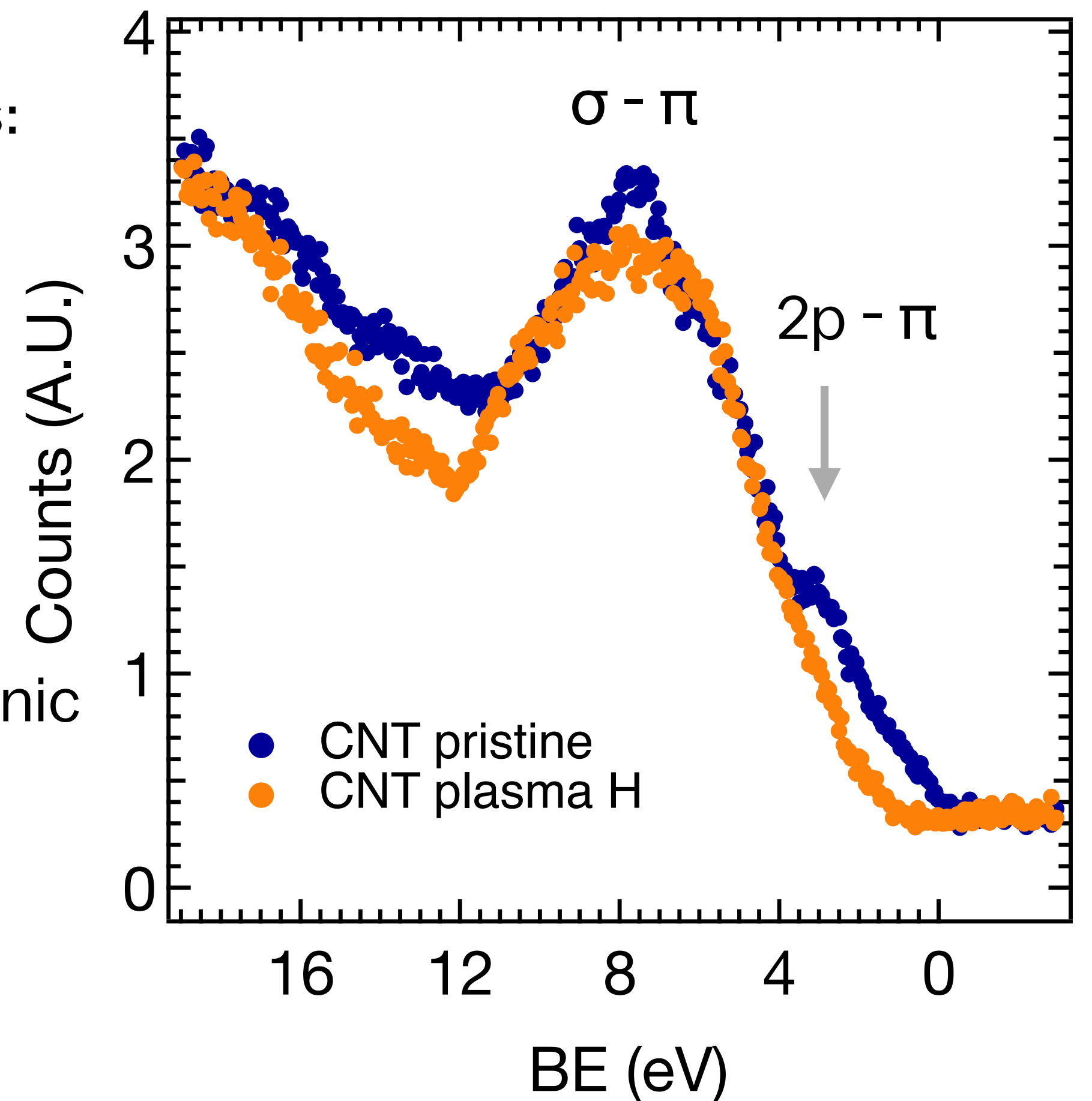
- **WF lowers** from $4.33 \pm 0.05 \text{ eV}$ to $3.81 \pm 0.05 \text{ eV}$

Depletion of the electronic levels near Fermi level

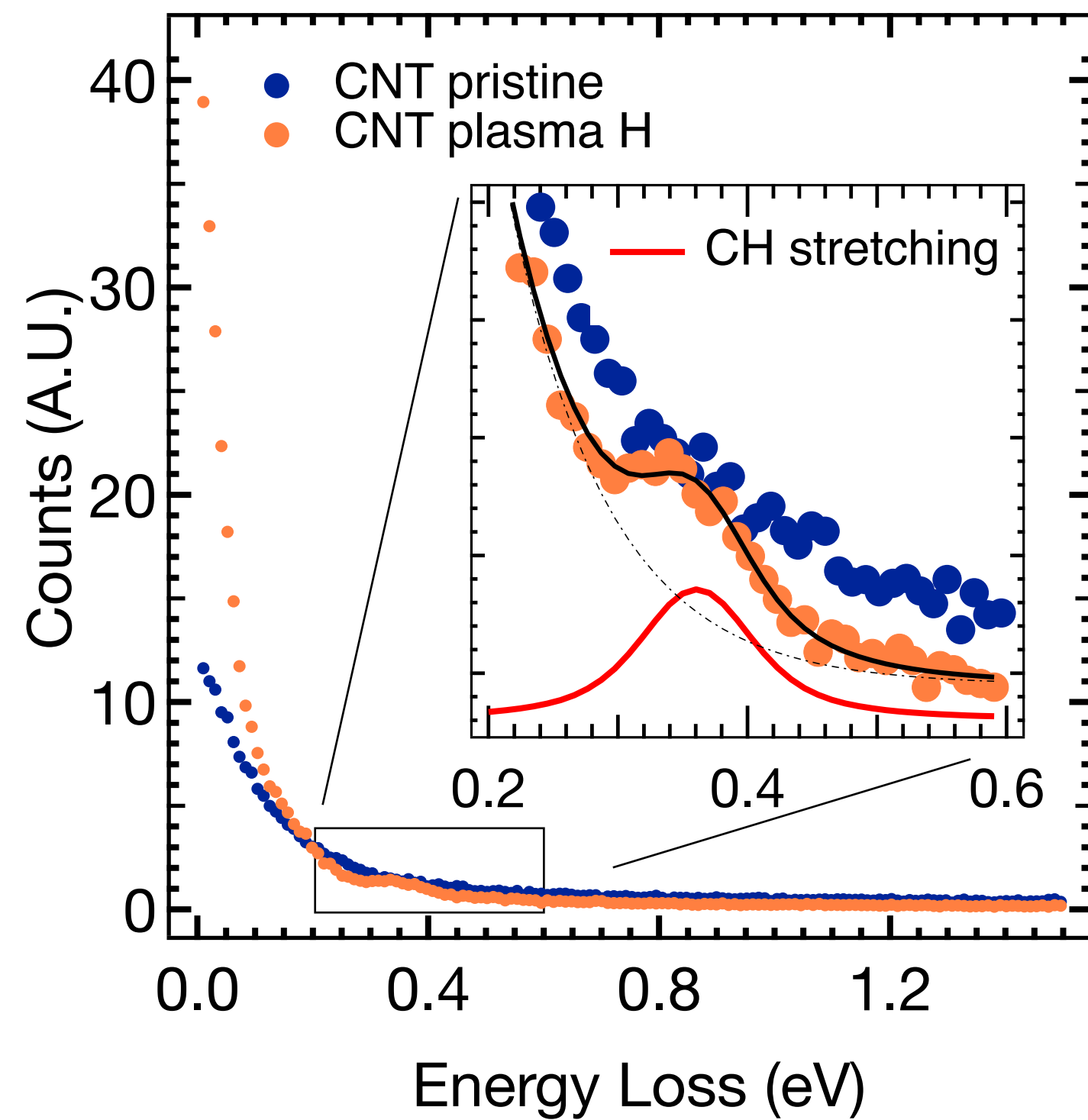
- **Gap opening**

Valence Band

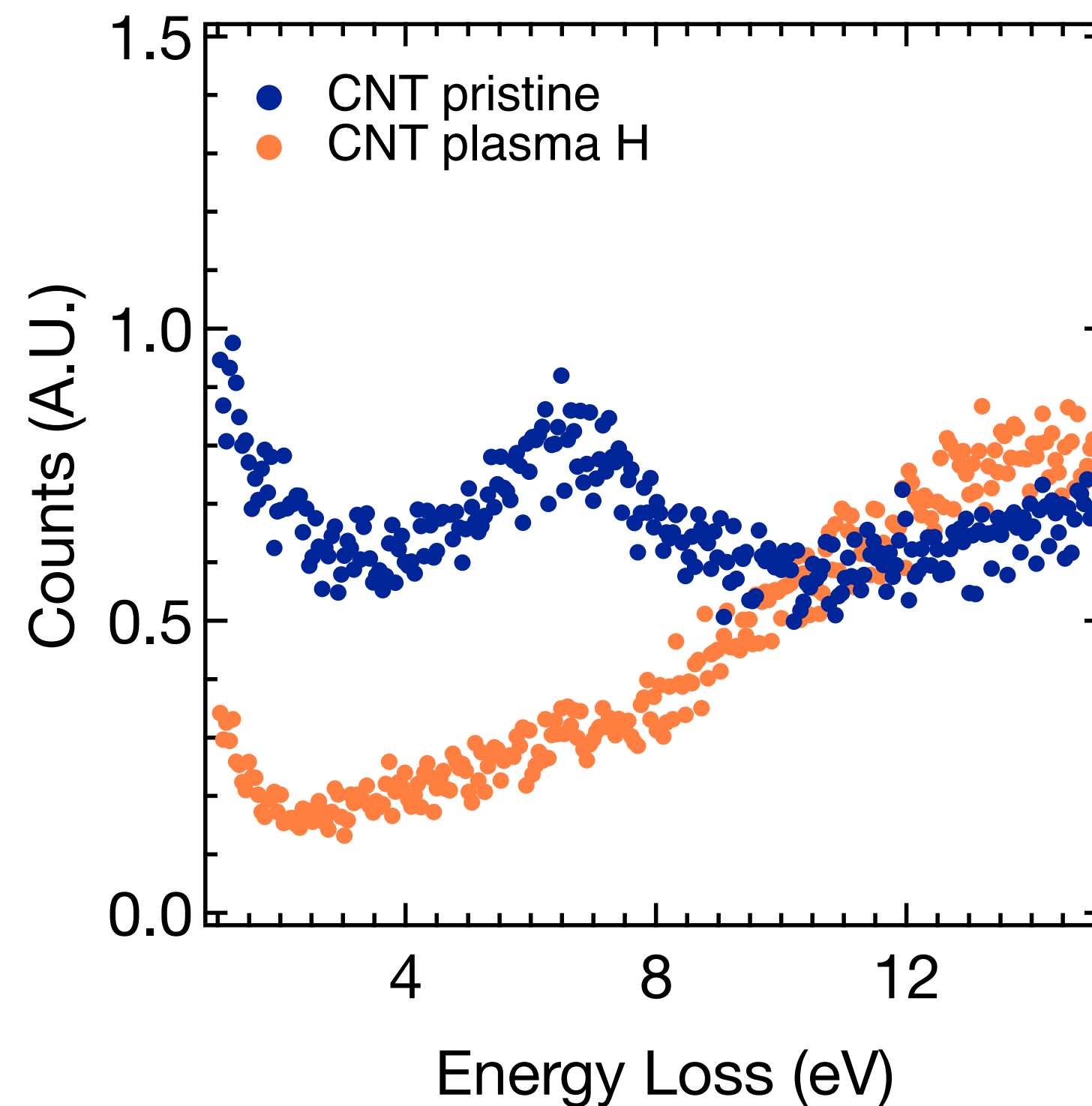
He II



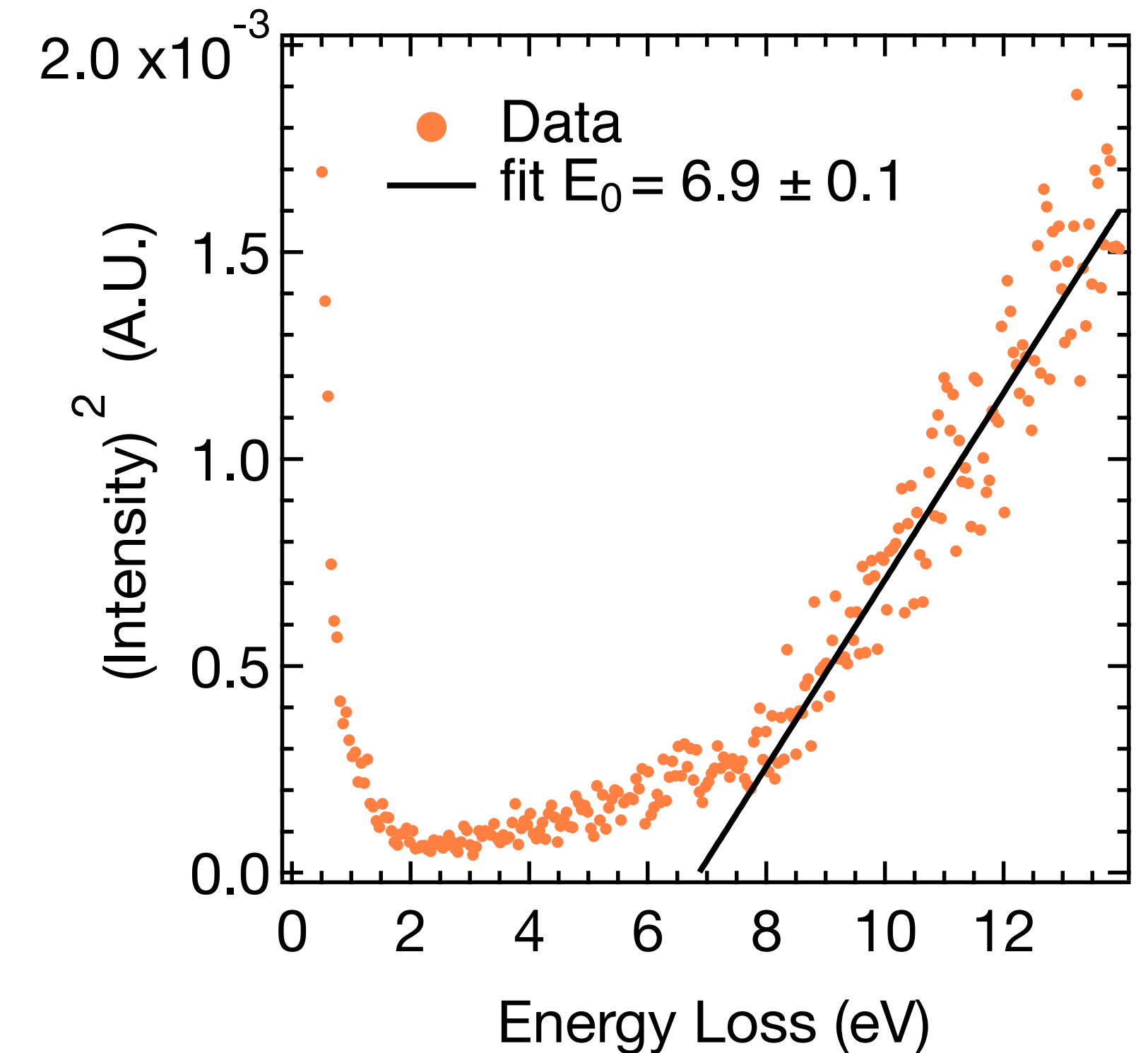
Electron Energy Loss Spectroscopy



○ **CH stretching** appears at ~ 0.36 eV

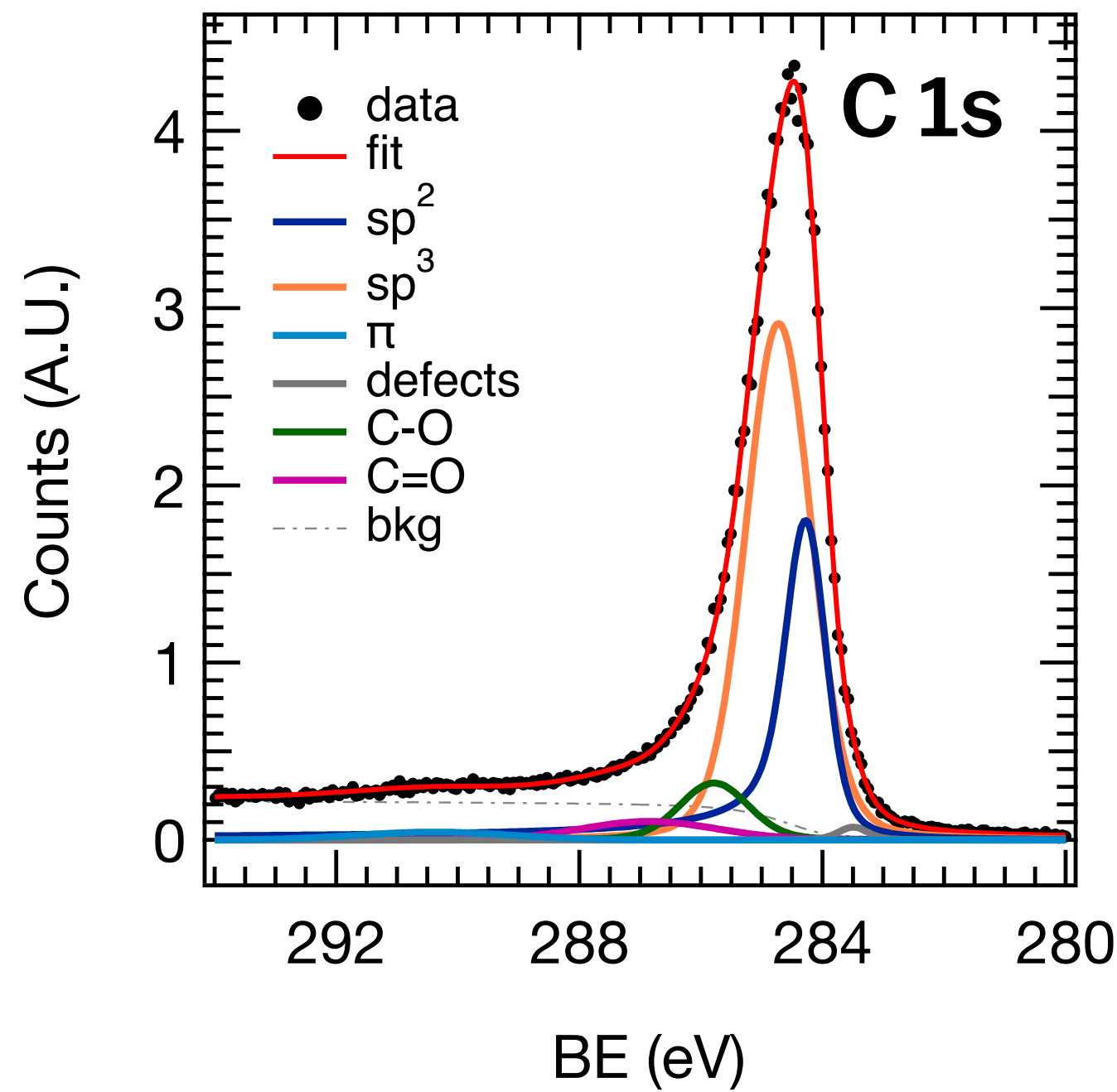


○ Quenching of the π plasmon and low energy losses



○ Wide **band gap** opening ~ 6.9 eV

Hydrogen Plasma vs Thermal Cracking Hydrogenation



$$I_{sp3} / (I_{sp2} + I_{sp3}) \approx 67\%$$

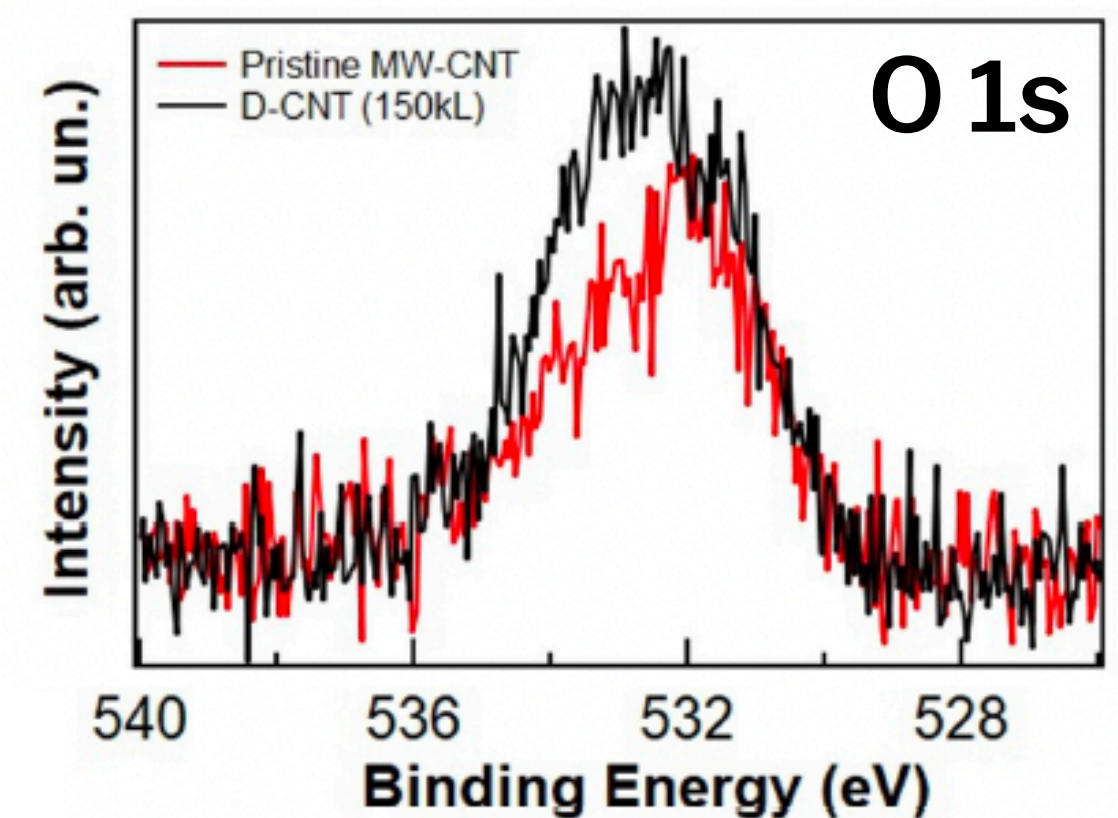
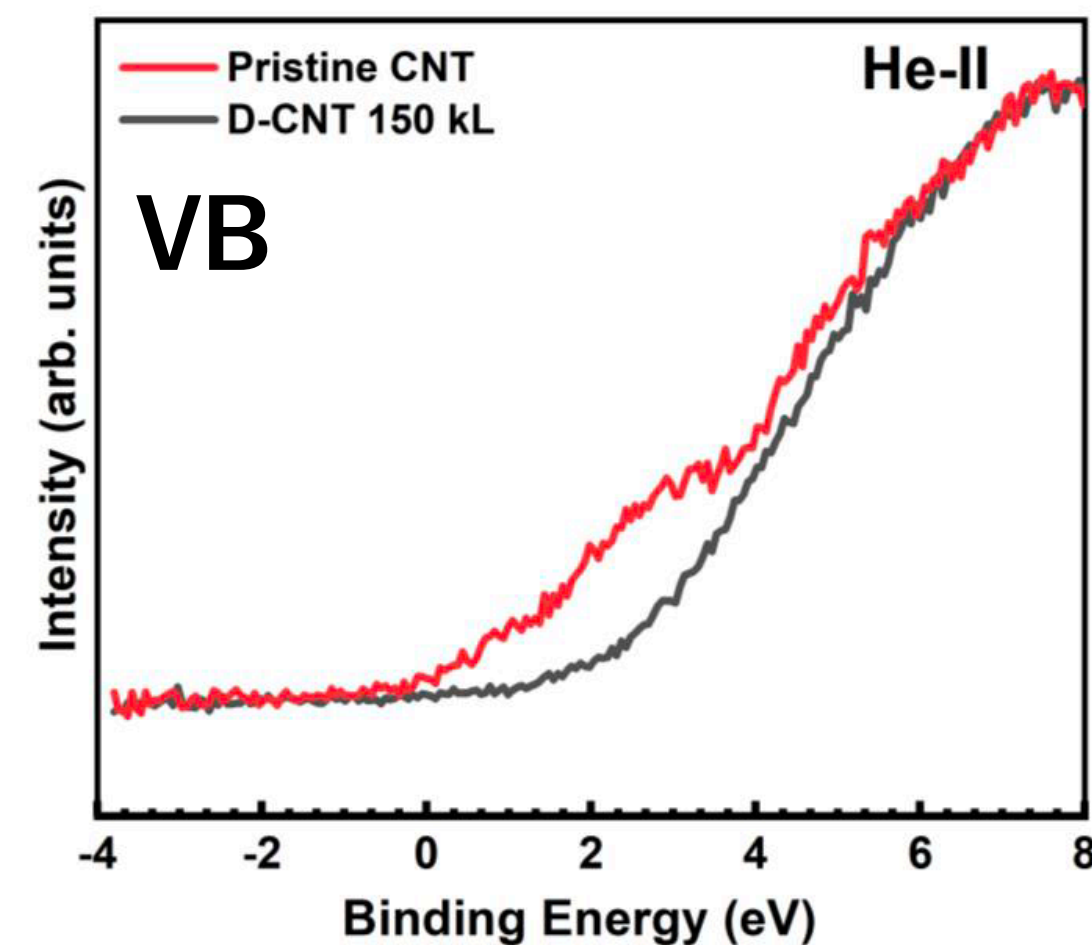
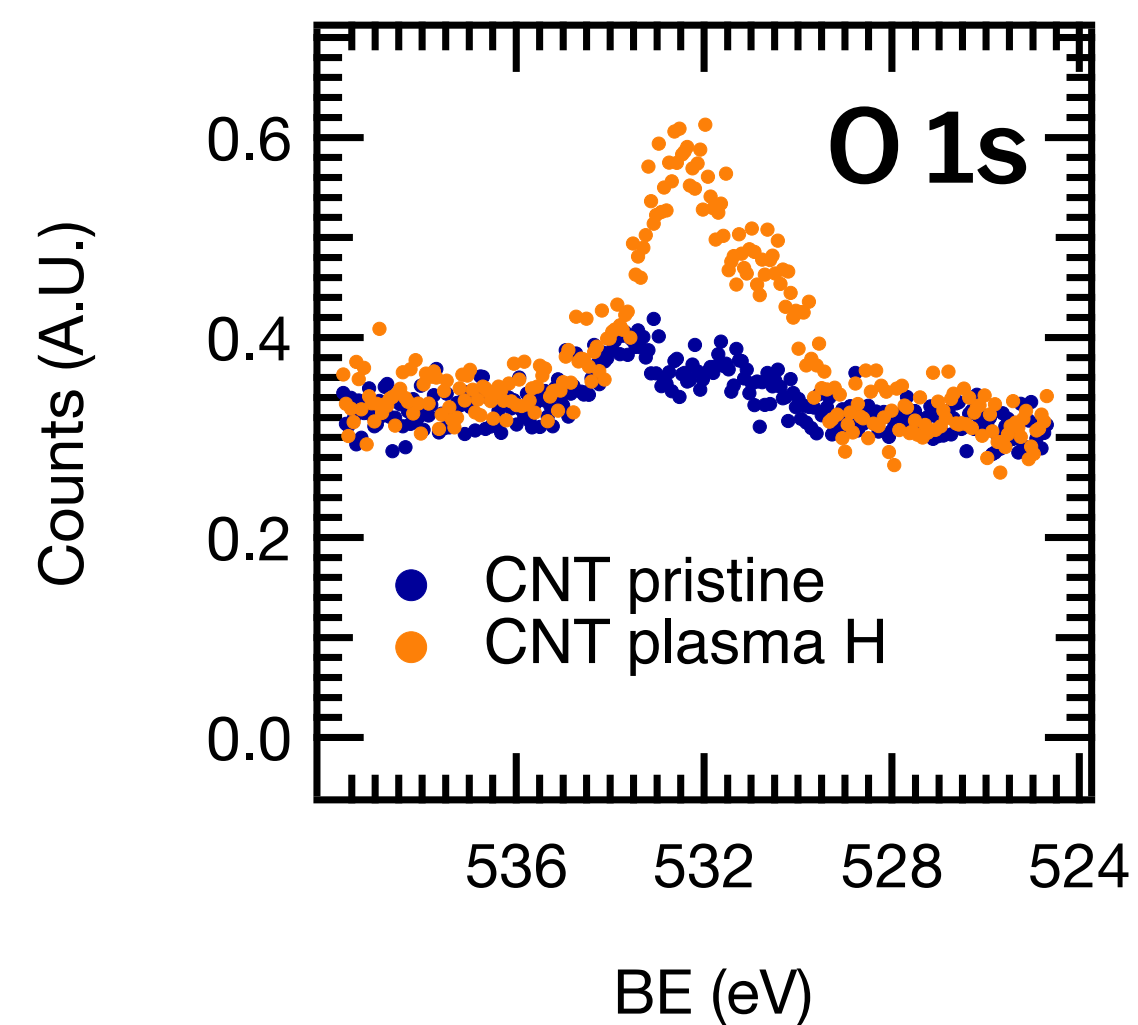
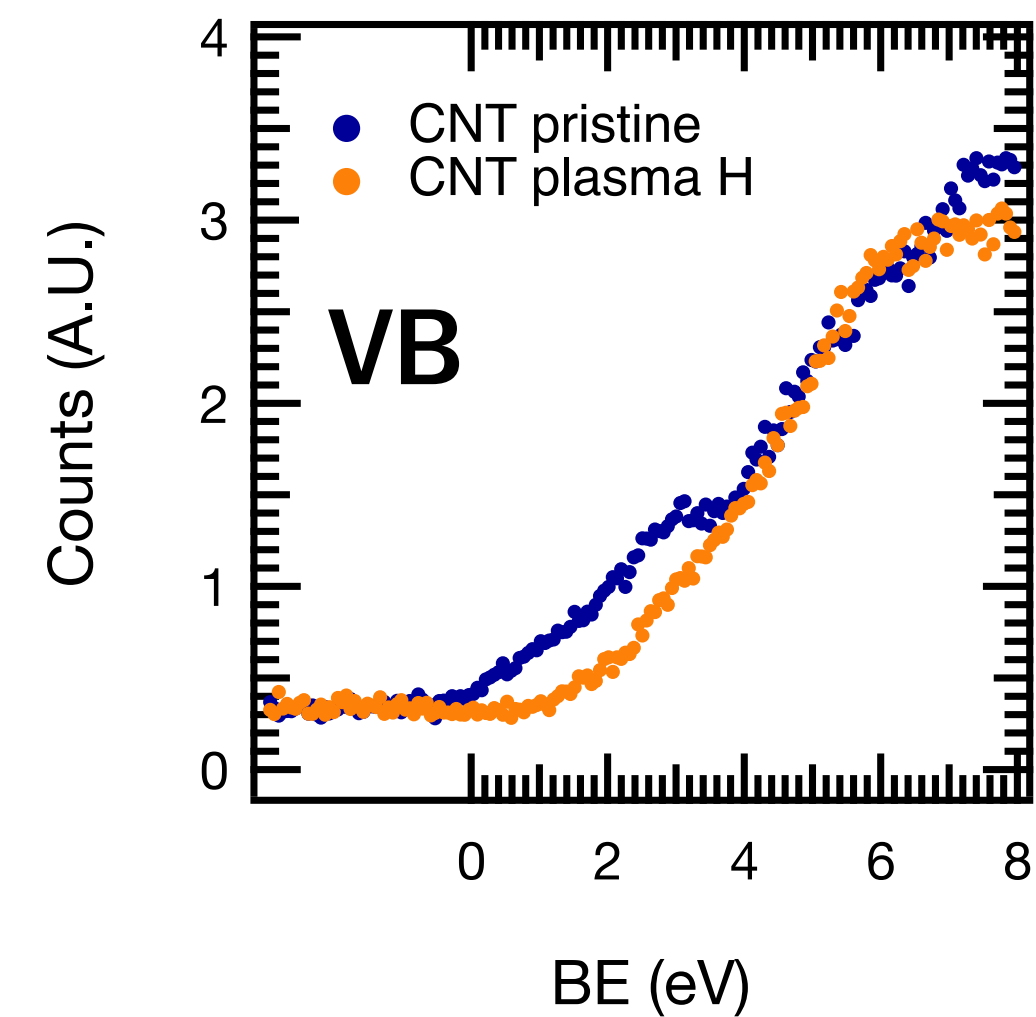
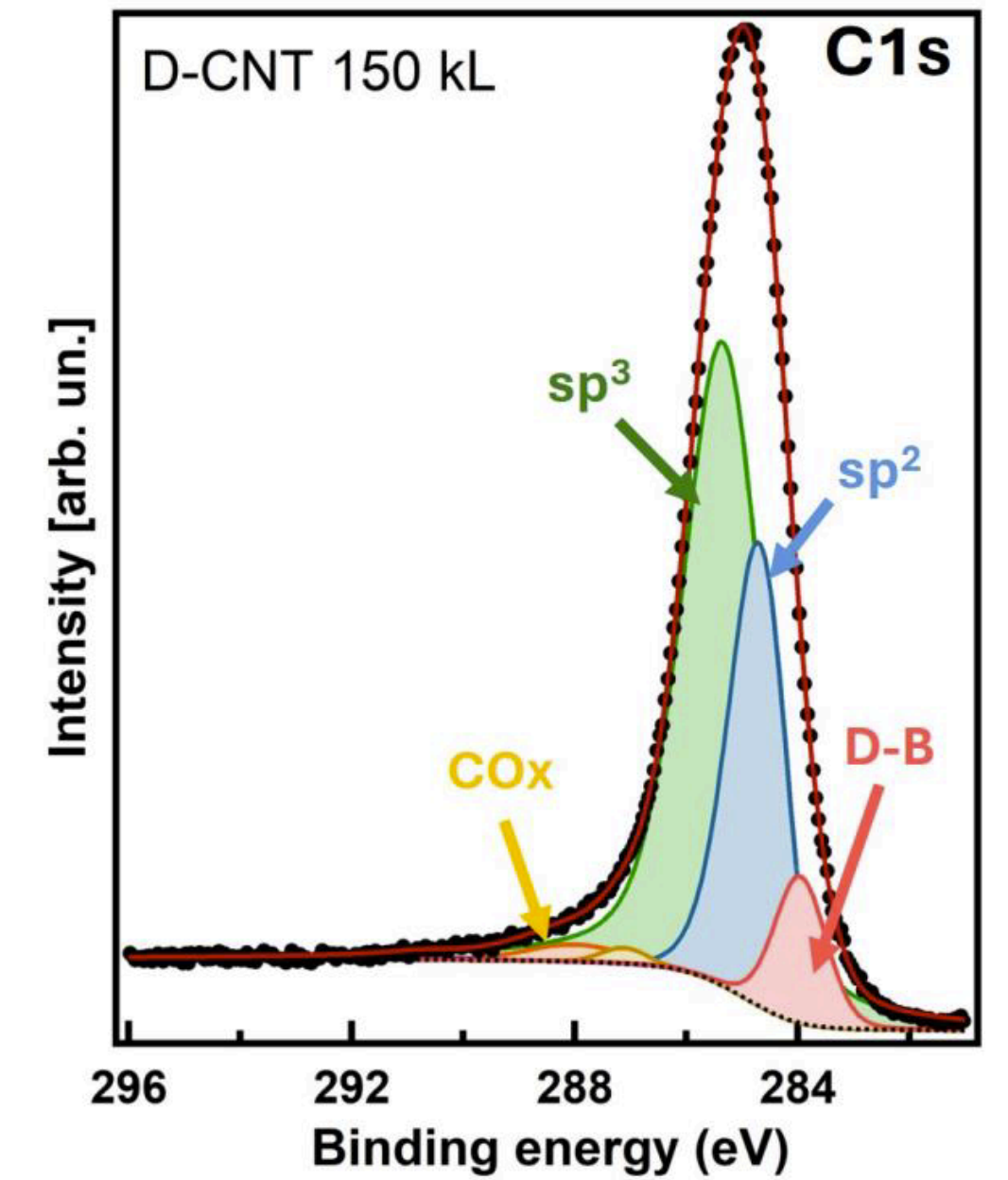
$$WF = 3.81 \pm 0.05 \text{ eV}$$

Atomic Deuterium bonding to Multi-Walled Carbon Nano Tubes

Sammar Tayyab et al., to be published

$$I_{sp3} / (I_{sp2} + I_{sp3}) \approx 70\%$$

$$WF = 3.84 \pm 0.05 \text{ eV}$$



A successful plasma hydrogenation of CNT

- sp^2 and π plasmon lowering, sp^3 increasing
- Work function decreases
- C-H vibration appears
- Gap opening

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Large amount of hydrogen!

Is it hydrogenated also in depth?

...but it is not perfectly clean

Also C-O and C=O increase

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Present/Future steps:

1. Compare thermal cracking and plasma hydrogenation in depth

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Present/Future steps:

1. Compare thermal cracking and plasma hydrogenation in depth
2. Make plasma hydrogenation during CNT growth

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Large amount of hydrogen!

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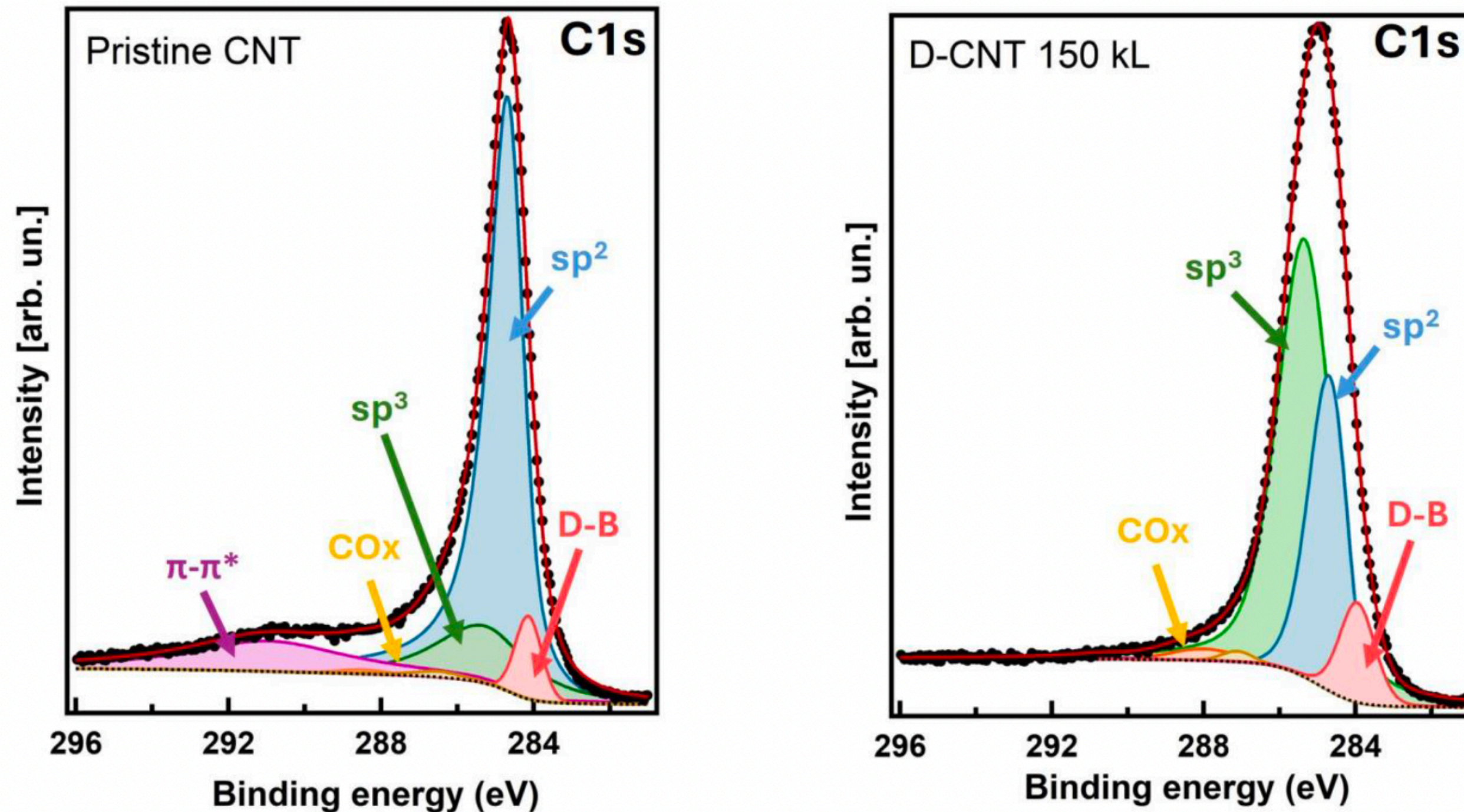
Also C-O and C=O increase

Present/Future steps:

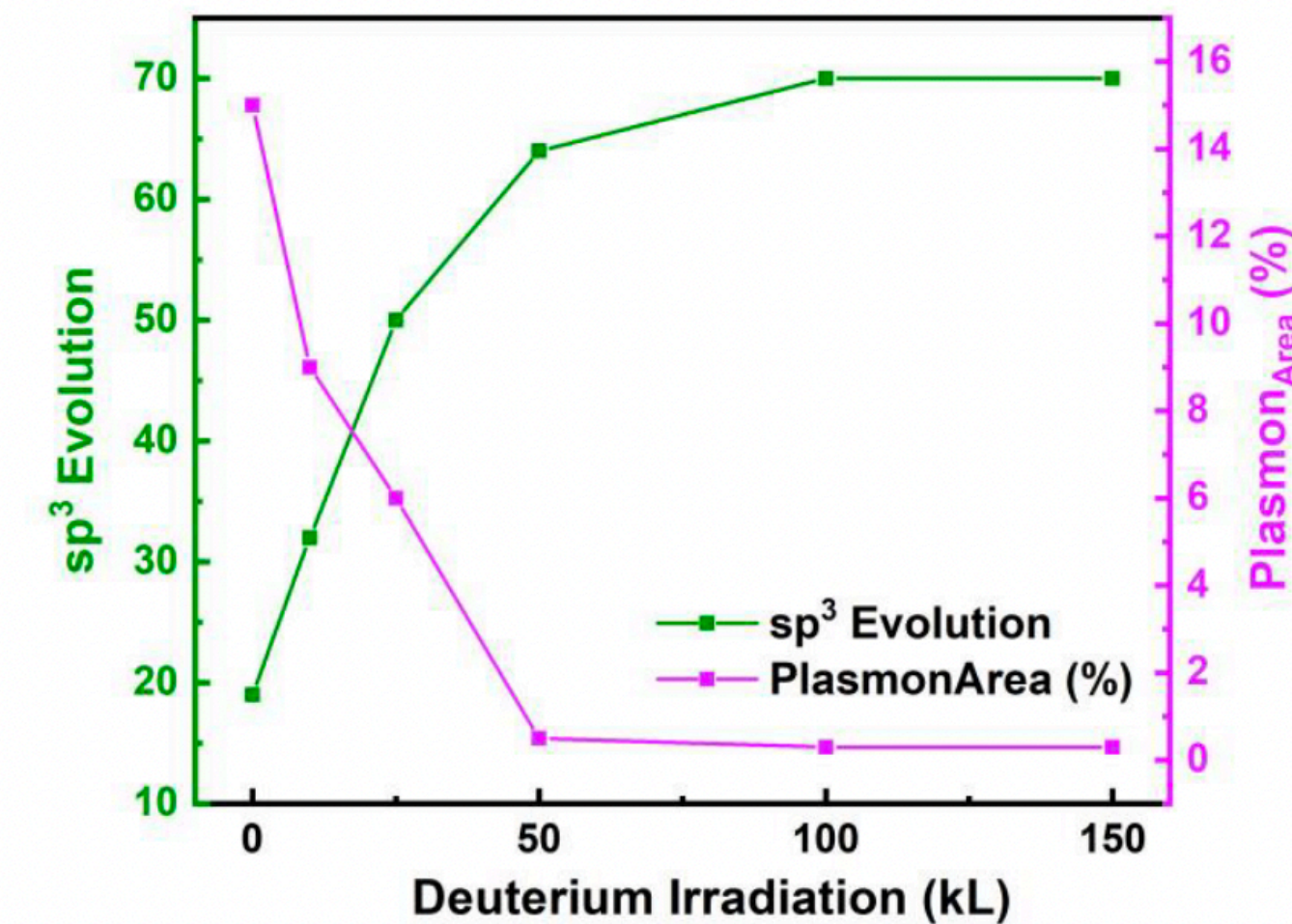
1. Compare thermal cracking and plasma hydrogenation in depth
2. Make plasma hydrogenation during CNT growth
3. Fine tuning of the parameters to limit oxygen contaminations

Back-up

C1s core level lineshape of Pristine and Highly Deuterated CNT sample.
A Quantitative Analysis:



	Pristine MWCNTs	D-CNT (150 kL)
Atomic D upload [sp3/(sp3+sp2)]	19%	70%



sp² component representative of perfect planar C bonding.
sp³ component is a sign of bond deformation and D C bonds.
plasmon associated to the π collective excitations.

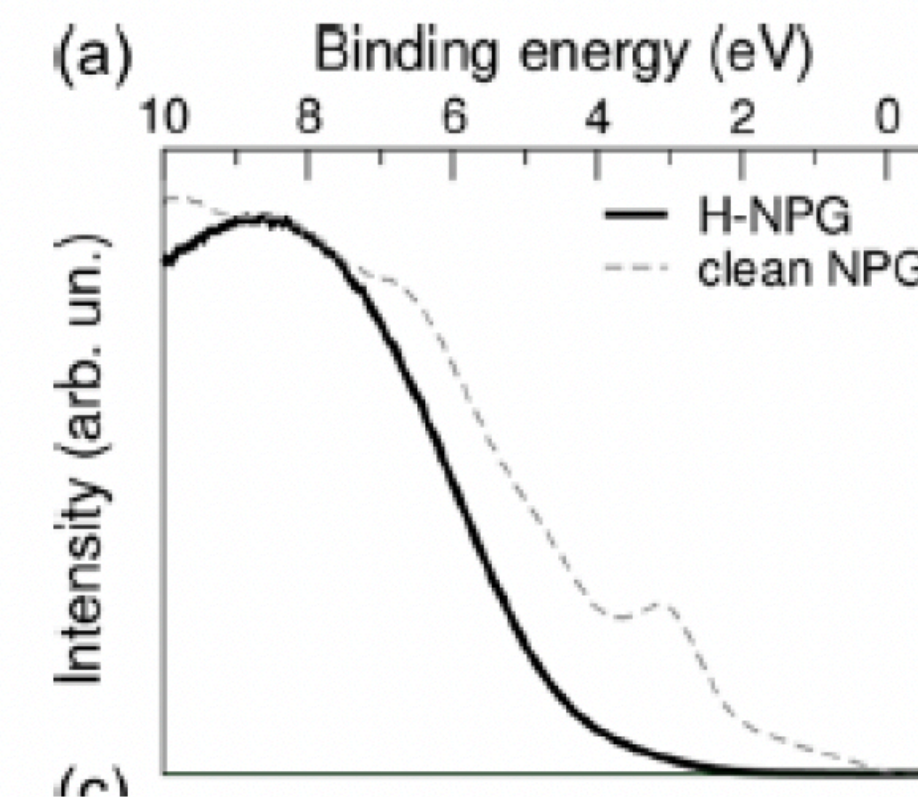
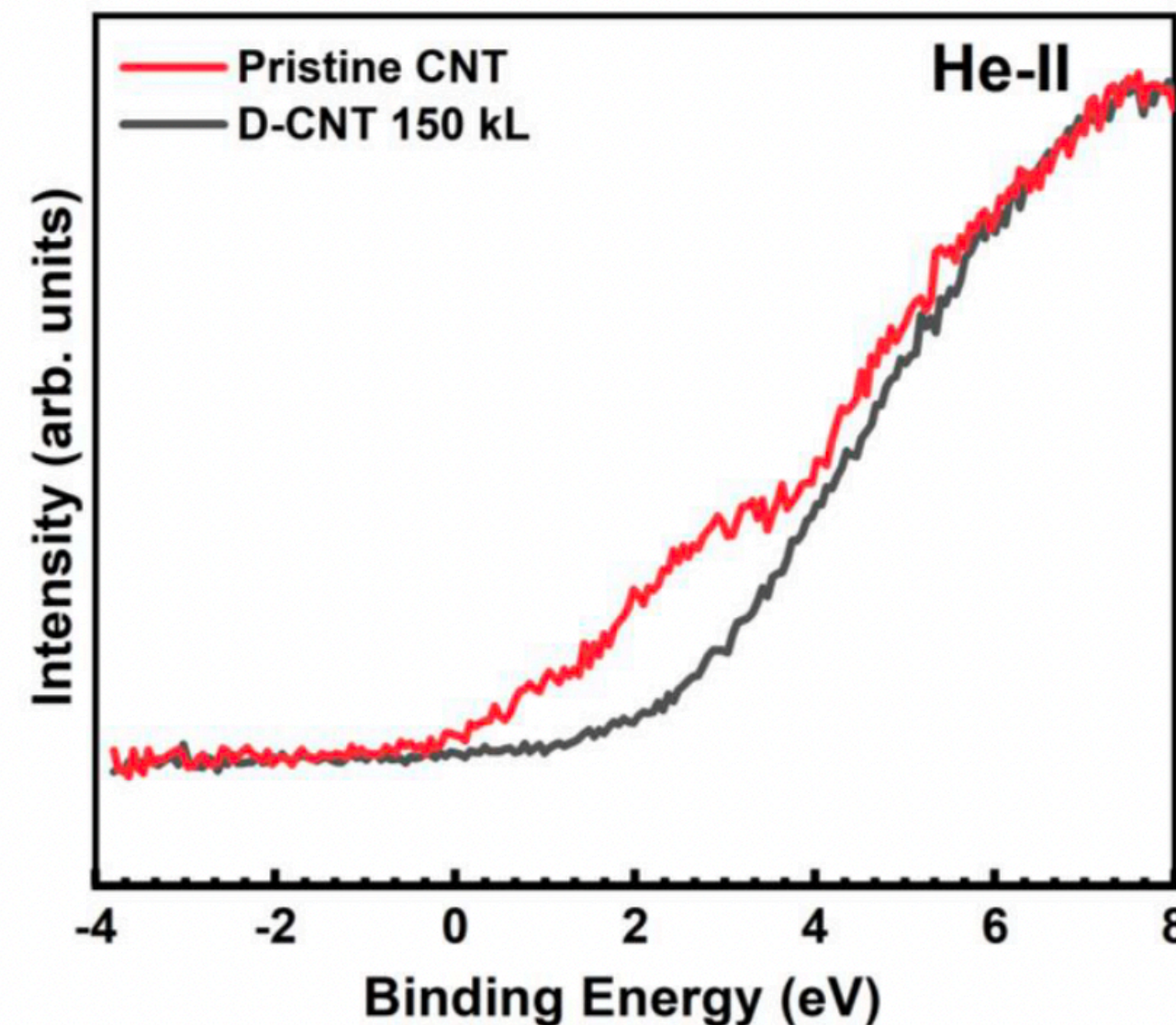
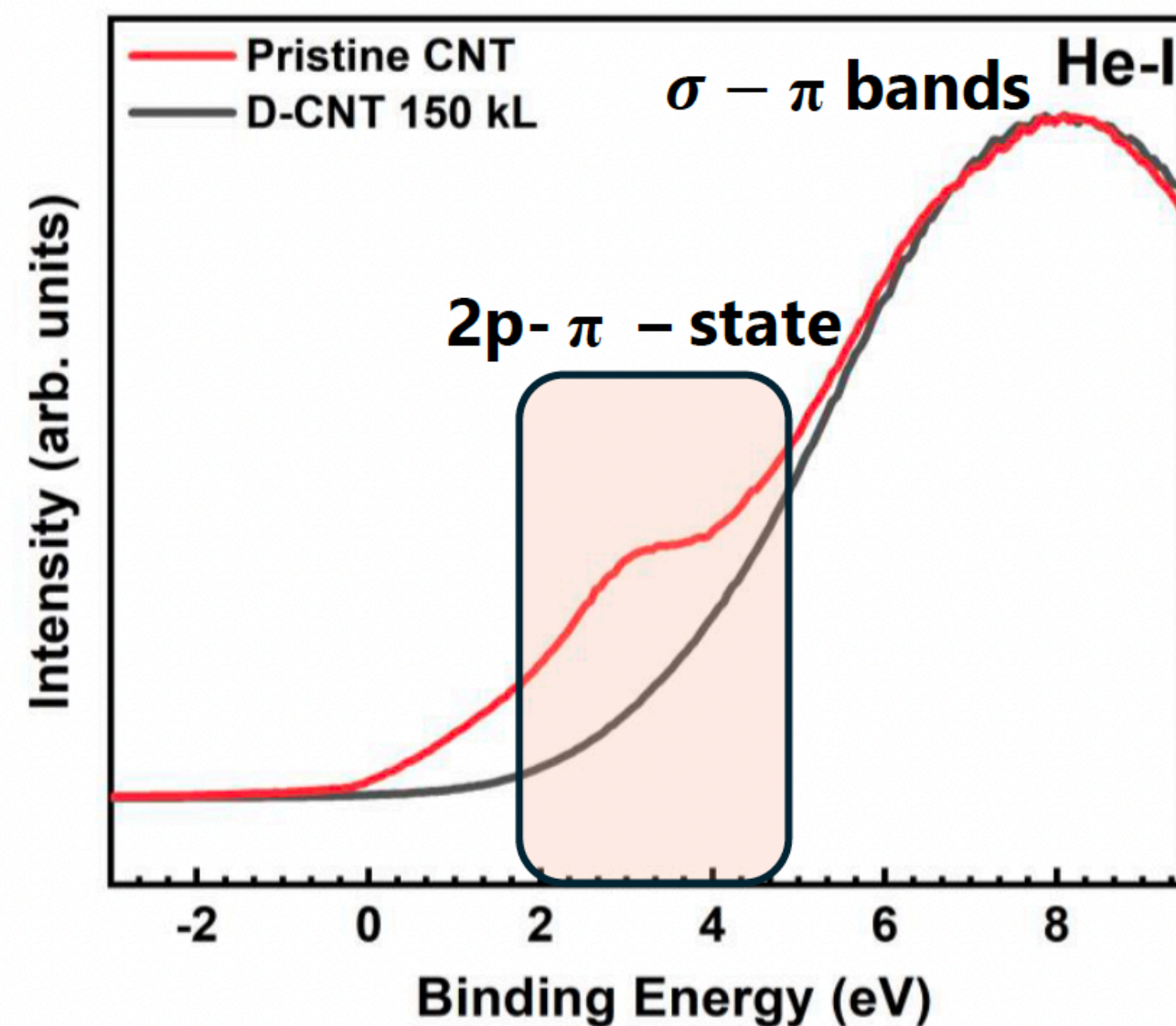
*** ~ 50% D-nanoporous graphene**

Ultraviolet Photoelectron Spectroscopy:

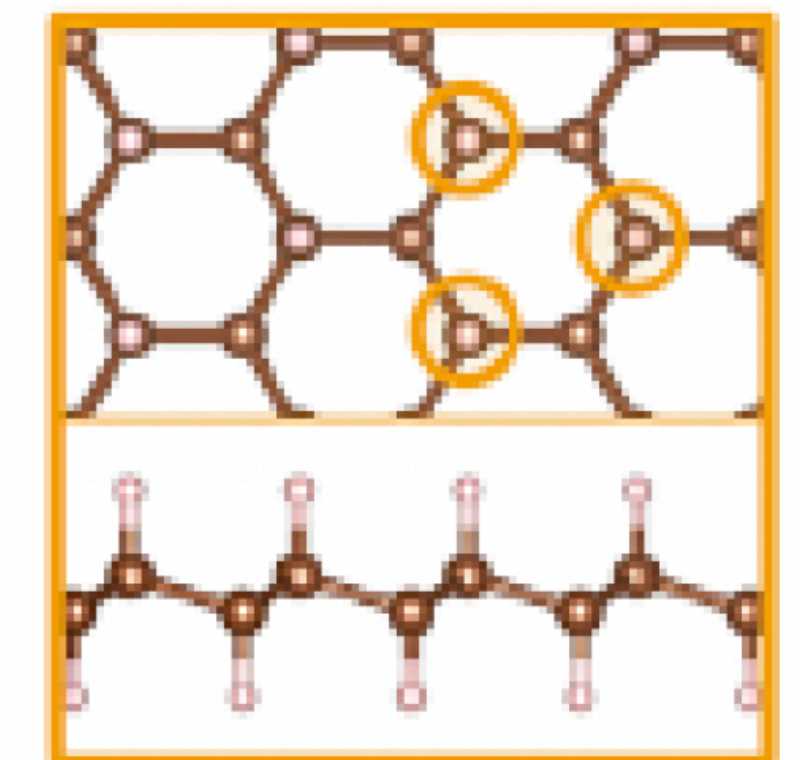
Valence bands Collection:

(He I photon energy 21.22 eV)

(He II photon energy 40.81 eV)



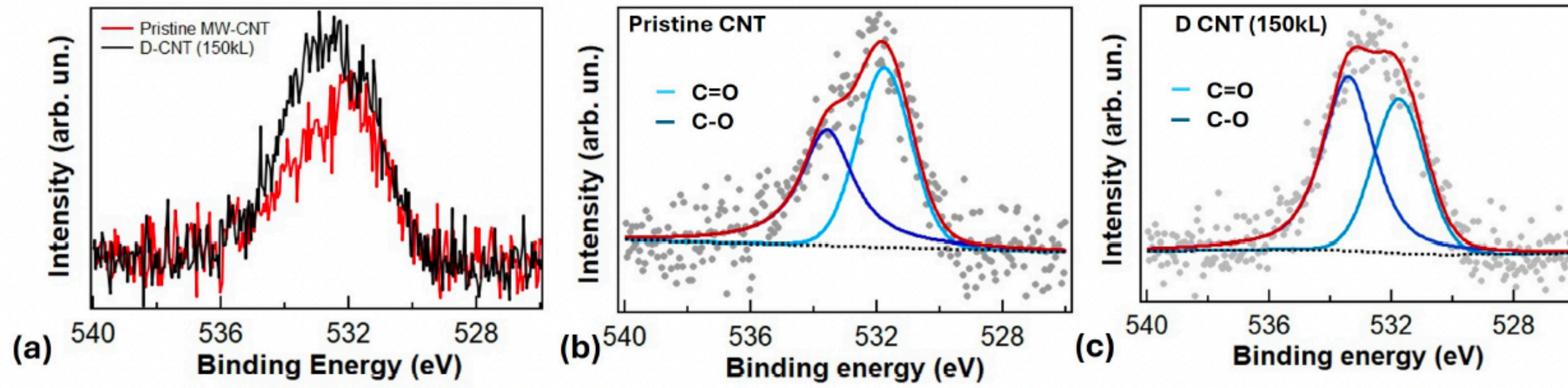
2side H-Gr



VB spectra of clean and H-Gr taken with He I.

Reduction in of 2p- π - states at 3.5 eV in D-CNT sample and

↓
Decrease in C2p- π electrons and
Reduction of graphitic carbon content

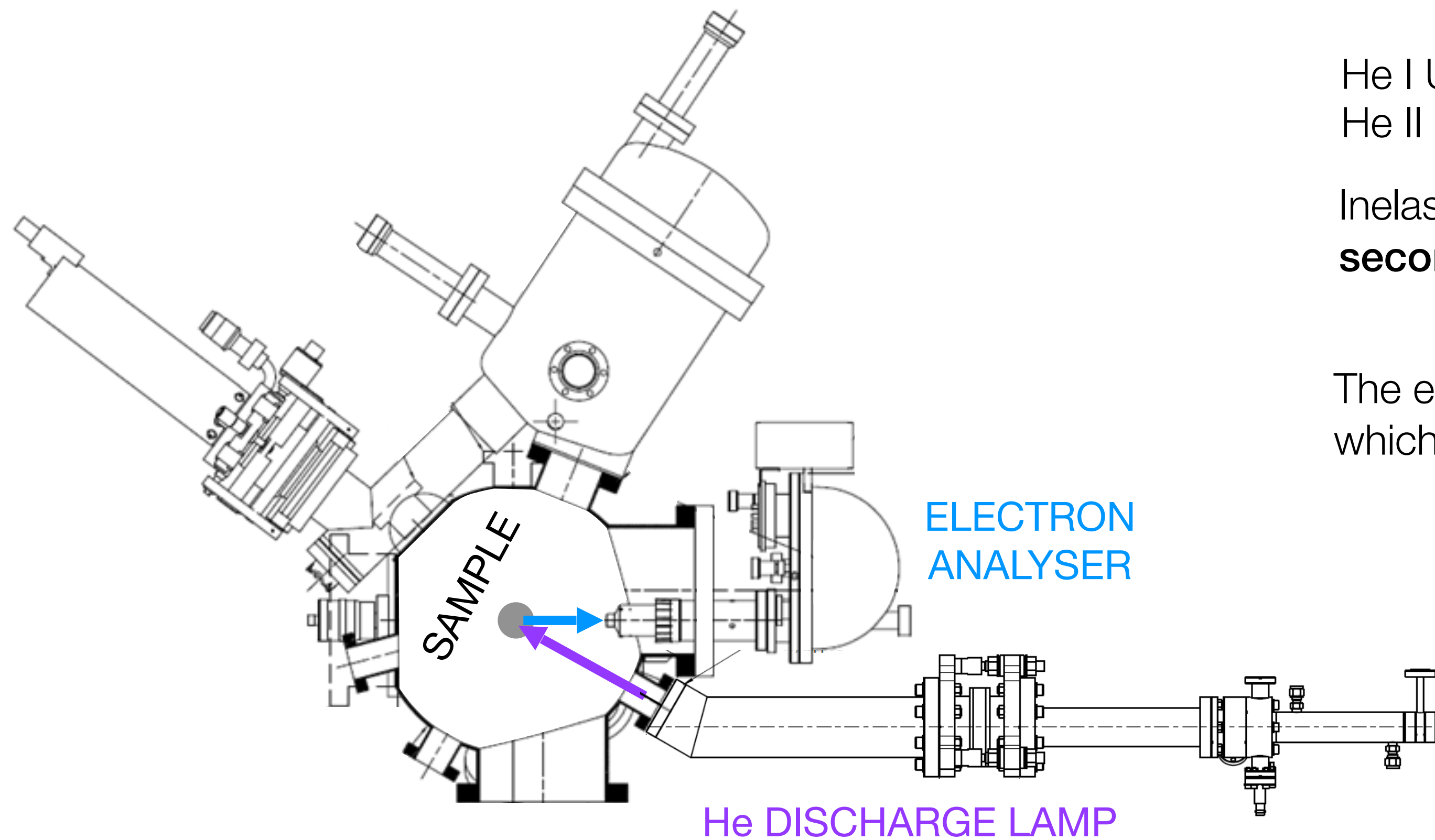


Pristine MW-CNT				
O1s component	BE (eV)	FWHM (eV)	Area/Area _{total}	
C=O	531.8	2.1	302	
C-O	533.5	1.9	276	
D-CNT MW-CNT				
O1s component	BE (eV)	FWHM (eV)	Area/Area _{total}	
C=O	531.8	1.9	335	
C-O	533.4	2.1	481	

C1s component	BE (eV)	Δ BE (eV)	FWHM (eV)	Area/Area _{total}	Θ (%)
sp ²	284.7	0	1.1	63	19
sp ³	285.3	0.6	2.9	16	
C-O	286.5	1.8	1.5	0.8	
C=O	288.5	3.8	1.5	0.4	
π - excitation	290.9	6.2	5.0	15	
vacancy - DB	284.1	-0.6	0.8	4	

C1s component	BE (eV)	Δ BE (eV)	FWHM (eV)	Area/Area _{total}	Θ (%)
sp ²	284.7	0	1.1	27	70
sp ³	285.3	0.6	1.8	62	
C-O	286.8	2.1	1.0	0.6	
C=O	288.0	3.3	2.1	1.6	
π - excitation	290.9	6.2	2.0	0.3	
vacancy - DB	284.0	-0.7	1.1	8	

The work function of a sample can be measured with **UPS**

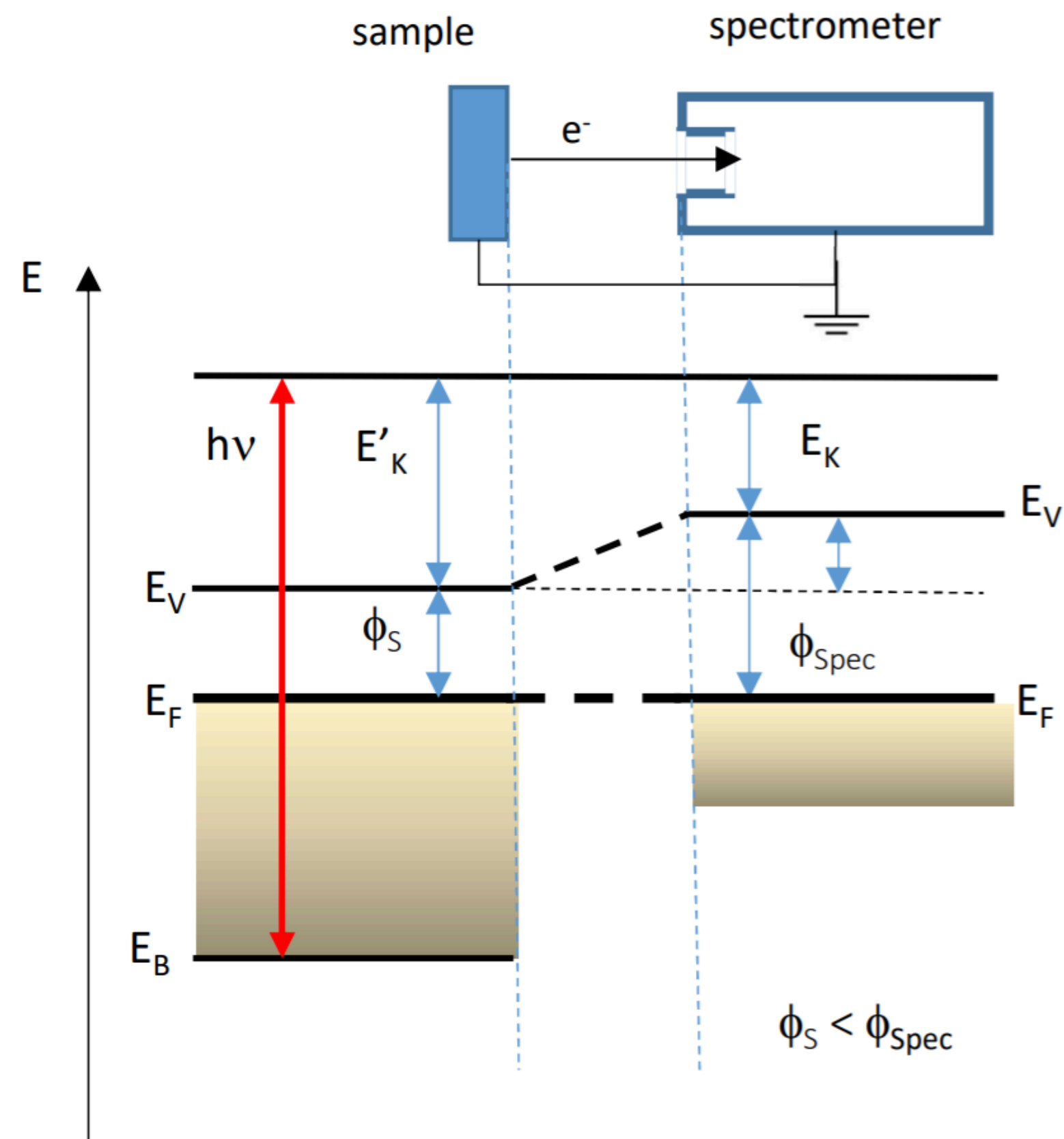


He I UV photon energy: $h\nu = 21.22 \text{ eV}$

He II UV photon energy: $h\nu = 40.8 \text{ eV}$

Inelastically scattered photoelectrons produce **secondary electrons**

The electrons emitted are collected by an electron analyzer which measures their **kinetic energy**



Analyzer point of view

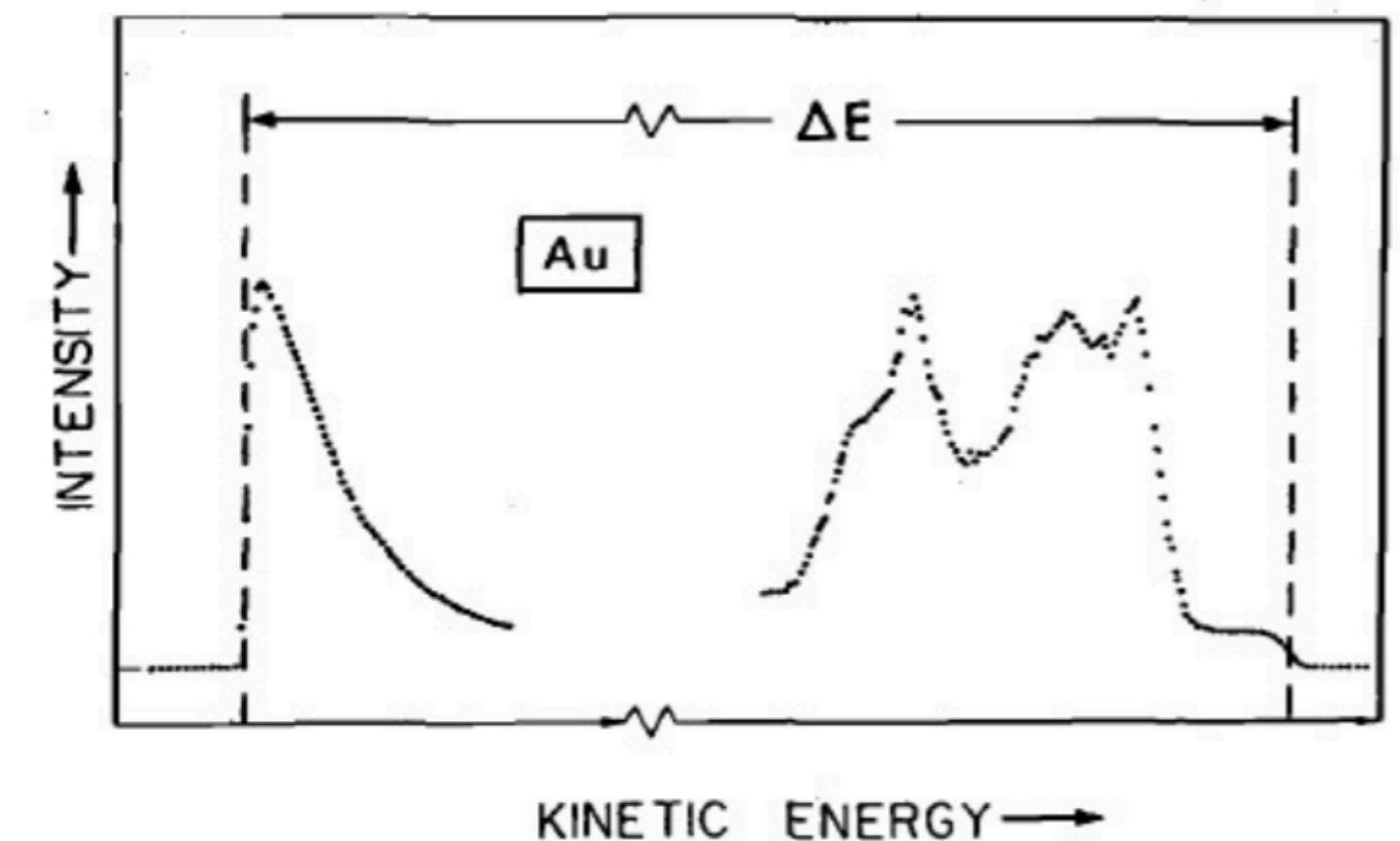
$$E_K^{min} = \phi_S - \phi_{Spec}$$

$$E_K^{max} = h\nu - \phi_{Spec}$$

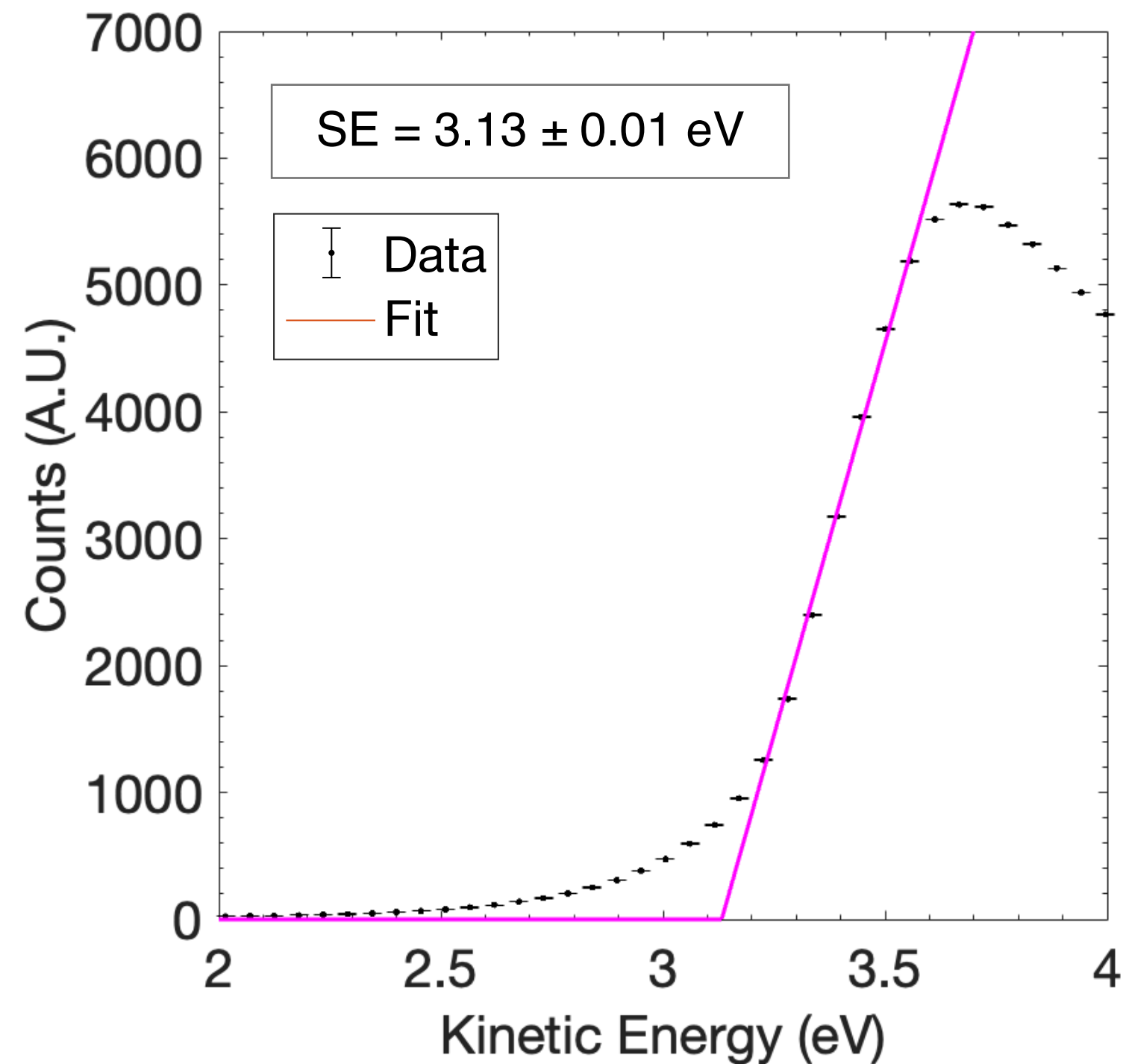
$$\Delta E_K = E_K^{max} - E_K^{min} = h\nu - \phi_S$$

- ◆ E_K max does not depend on the sample but only on the analyzer's work function
- ◆ E_K min depends on the sample and on the analyzer
- ◆ ΔE_K depends only on the sample

- ◆ a **potential difference** is applied to the sample with respect to the analyzer in order to measure the secondary electron onset



Secondary onset



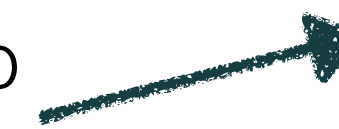
Linear Fit

$$y = m x + q$$

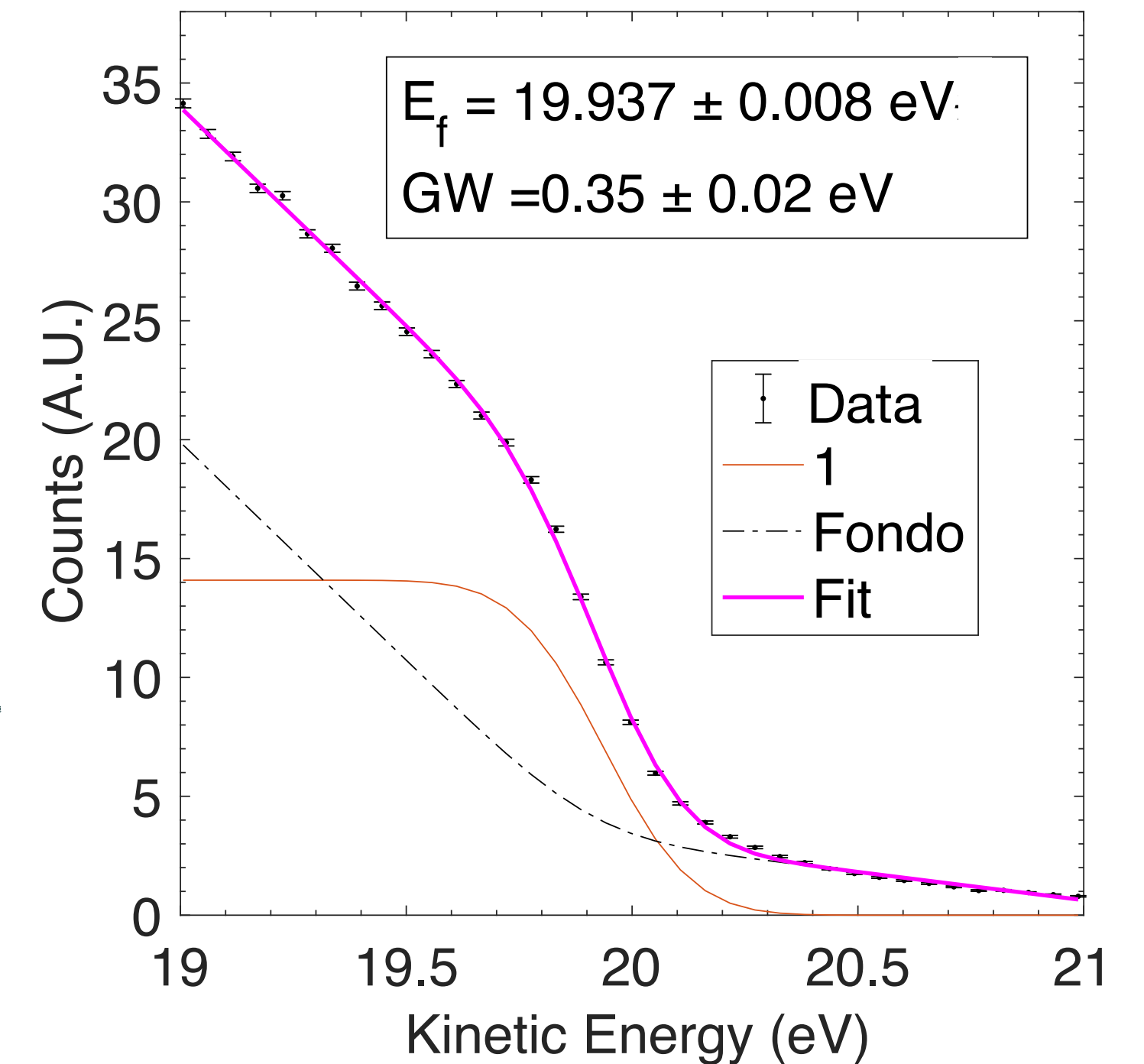
$$SE = - q / m$$

Sample polarized to $V_B = -3 \text{ V}$

Measured on a metal clip on the sample holder



Fermi Level



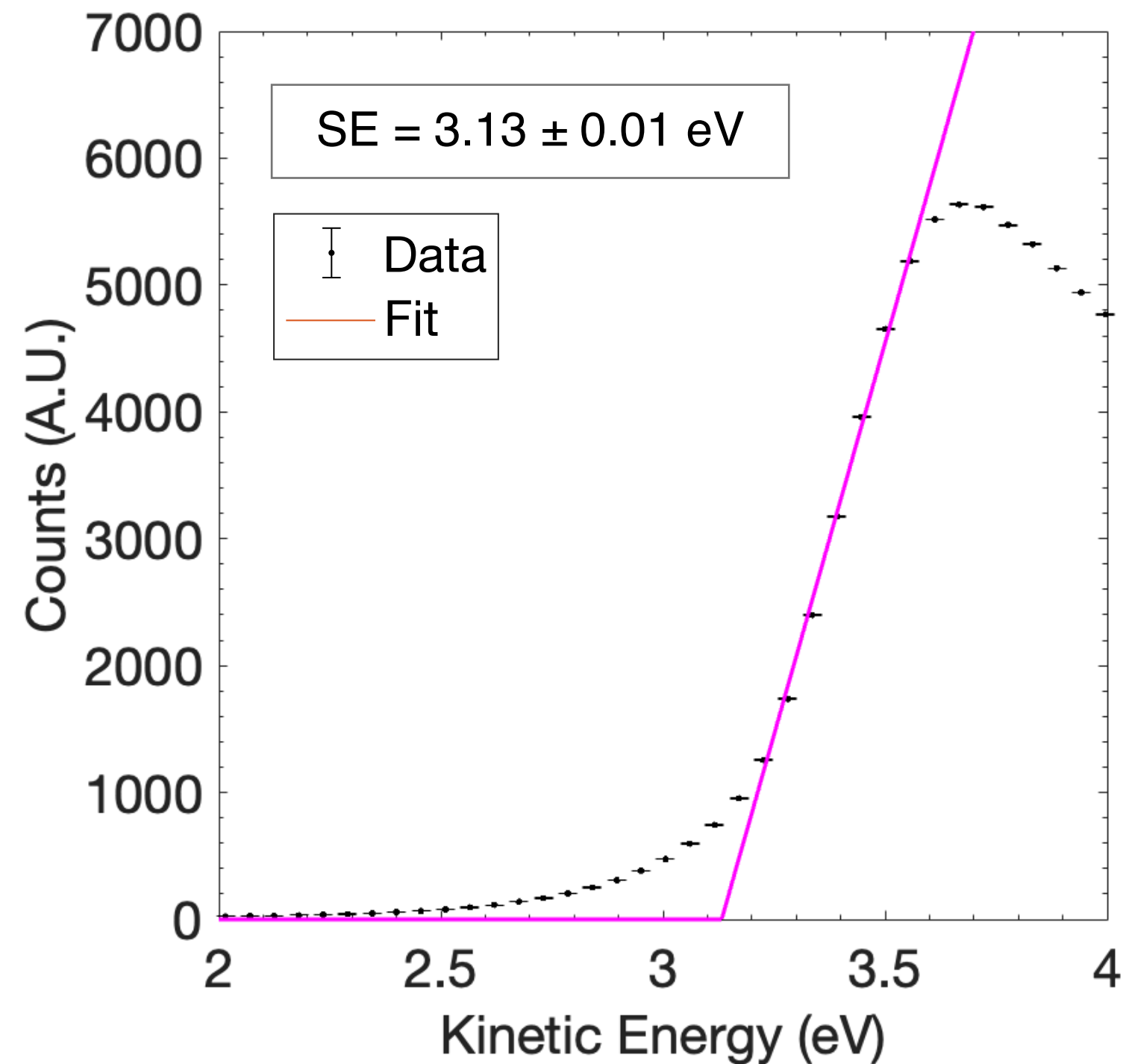
Fermi function convolution with a gaussian

$$f(E) = \frac{1}{e^{(E - E_F)/kT} + 1}$$

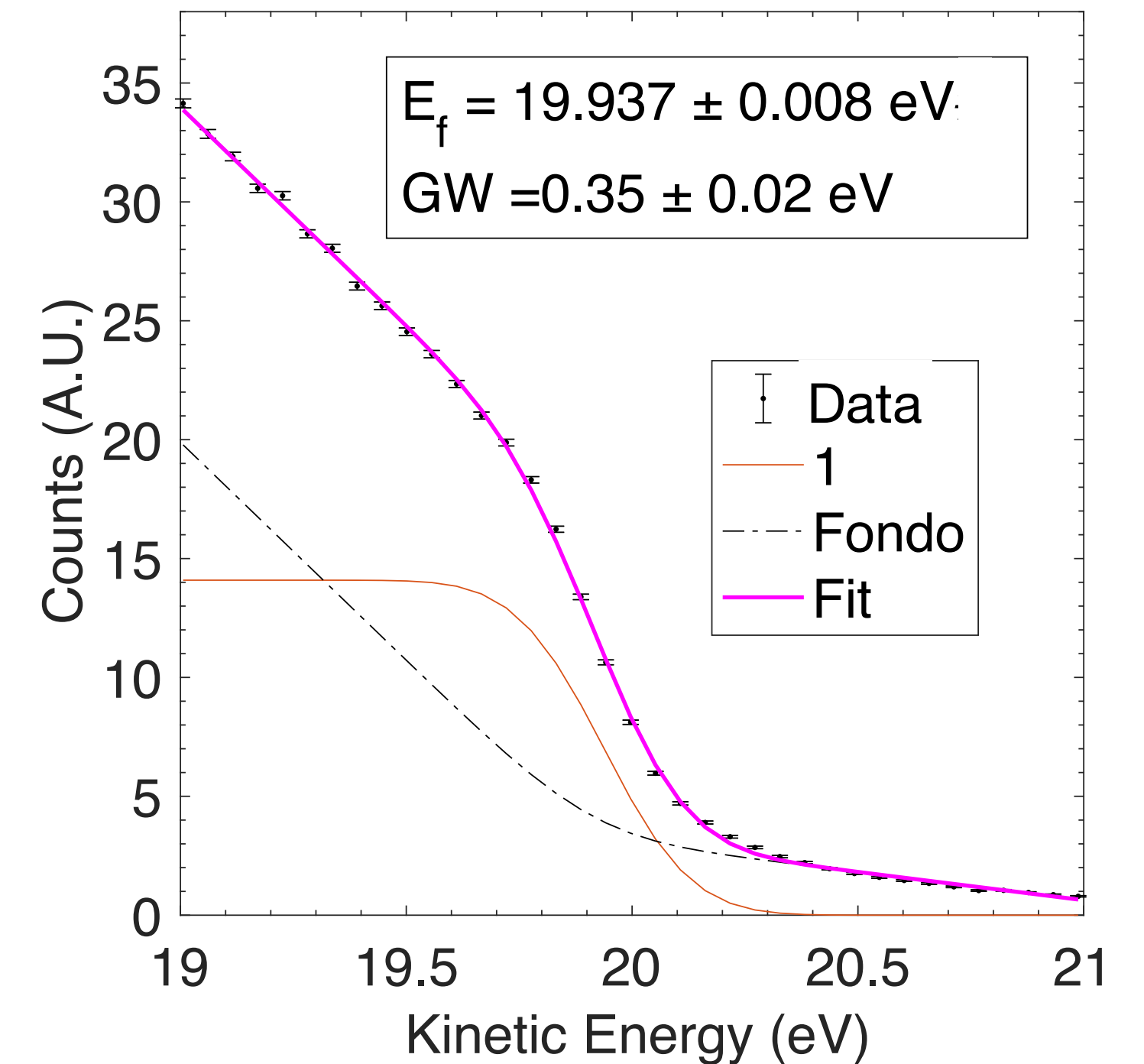
kT is fixed at 25 meV ($T = 293 \text{ K}$)

$$\phi_{\text{sample}} = h\nu - \Delta E_K = h\nu - (E_f - SE)$$

Secondary onset



Fermi Level

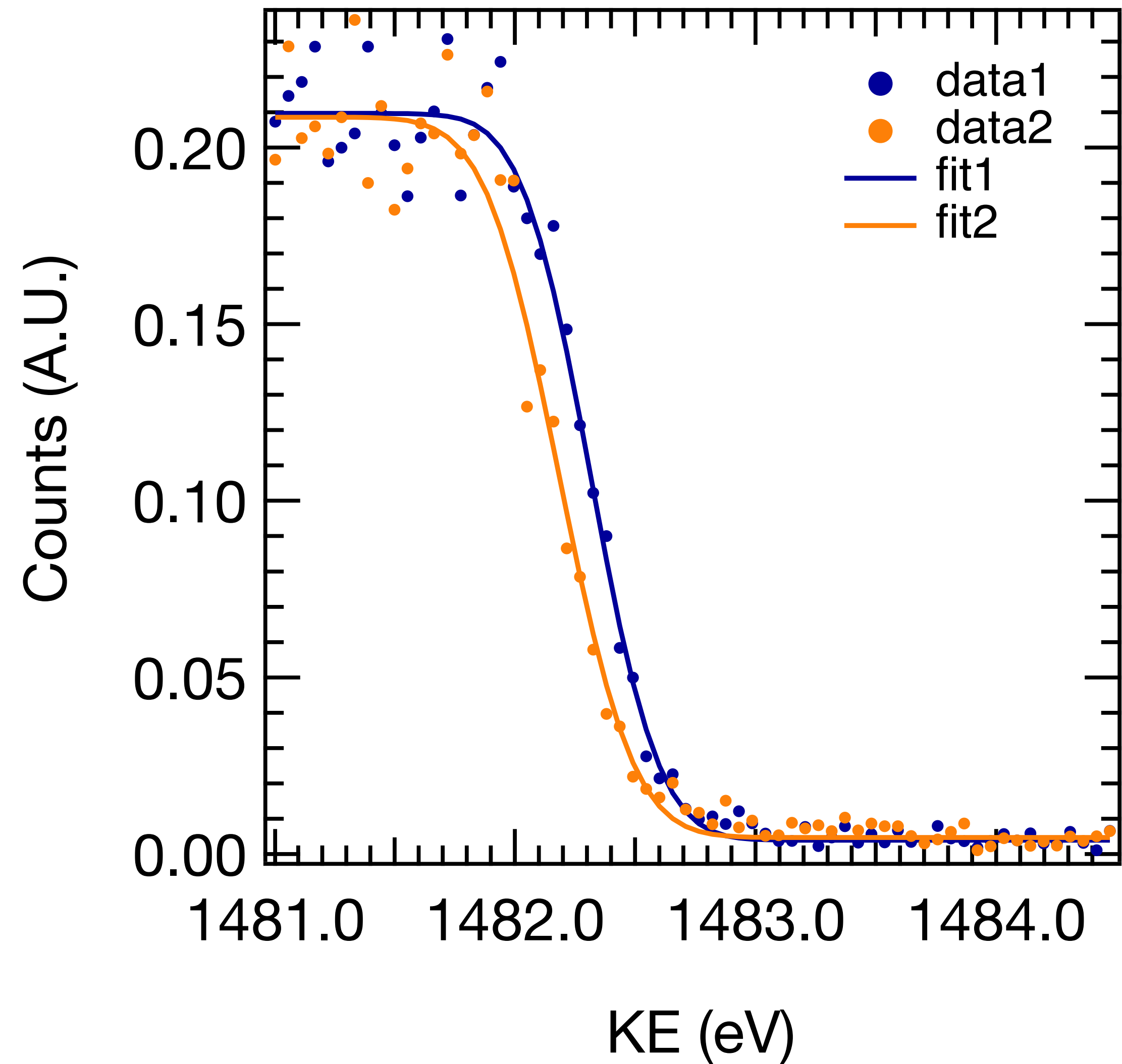
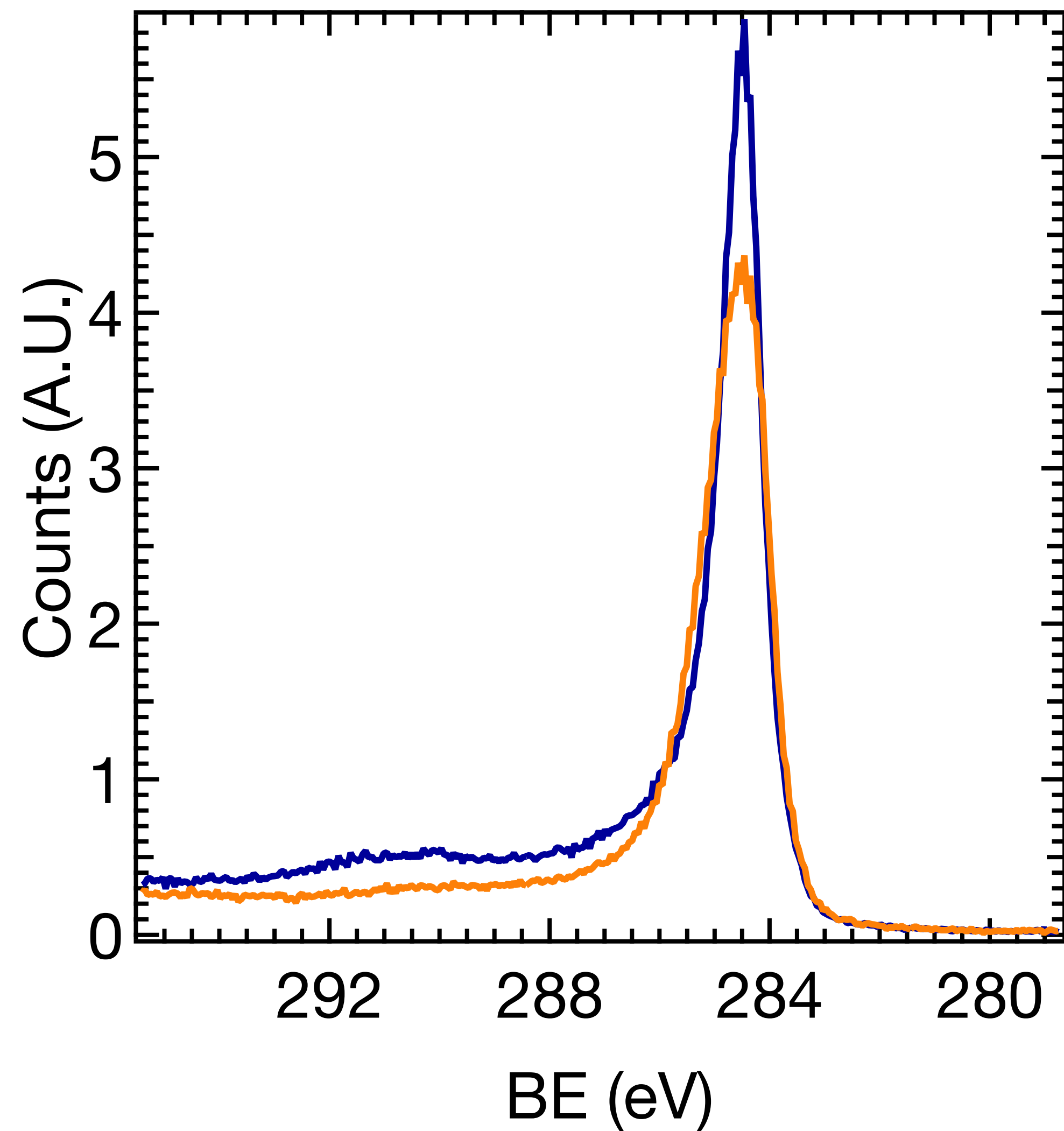


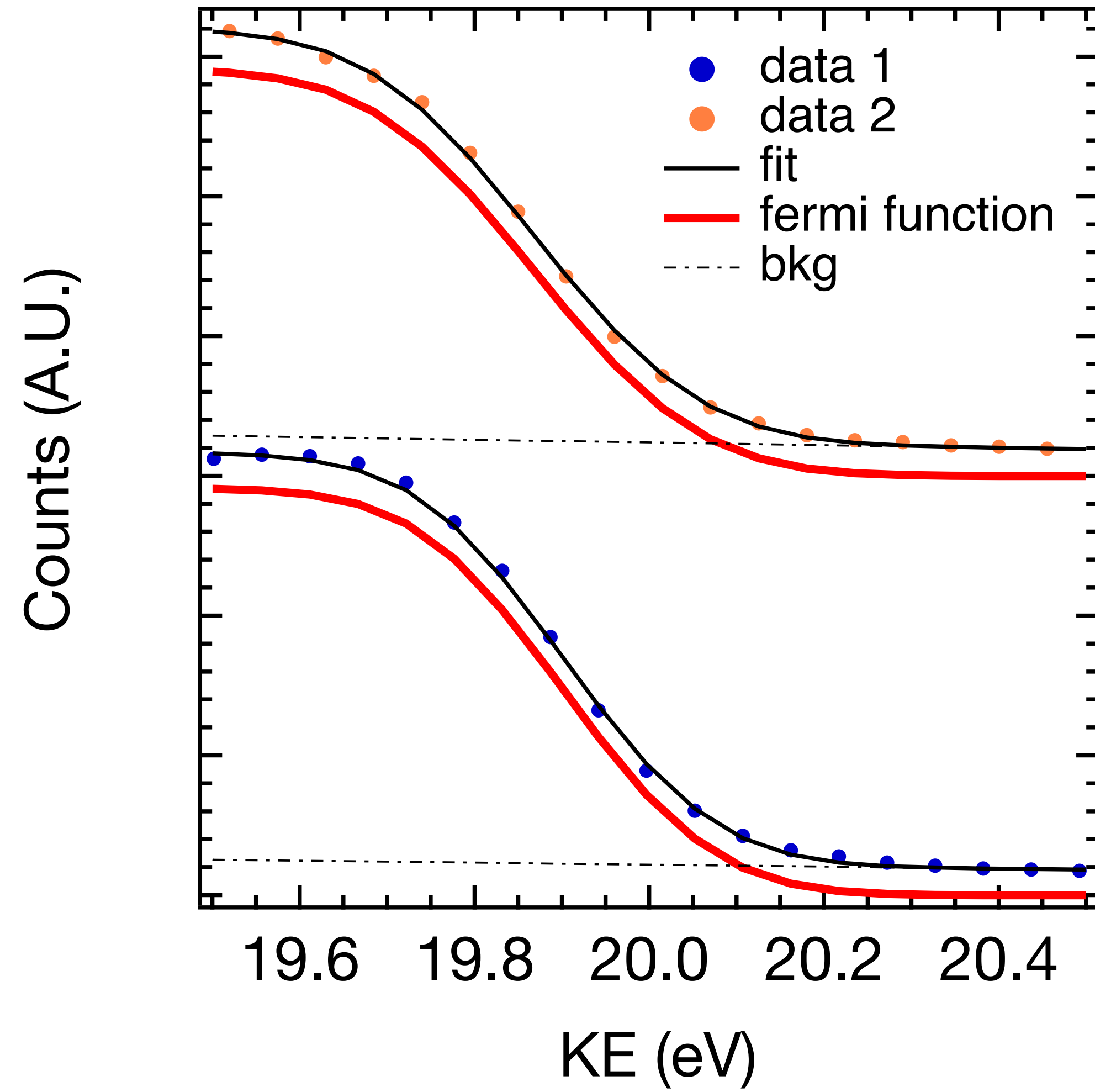
$$\phi_{\text{sample}} = h\nu - \Delta E_k = h\nu - (E_f - SE) = 21.22 - (19.937 - 3.13) = \mathbf{4.41 \text{ eV}}$$

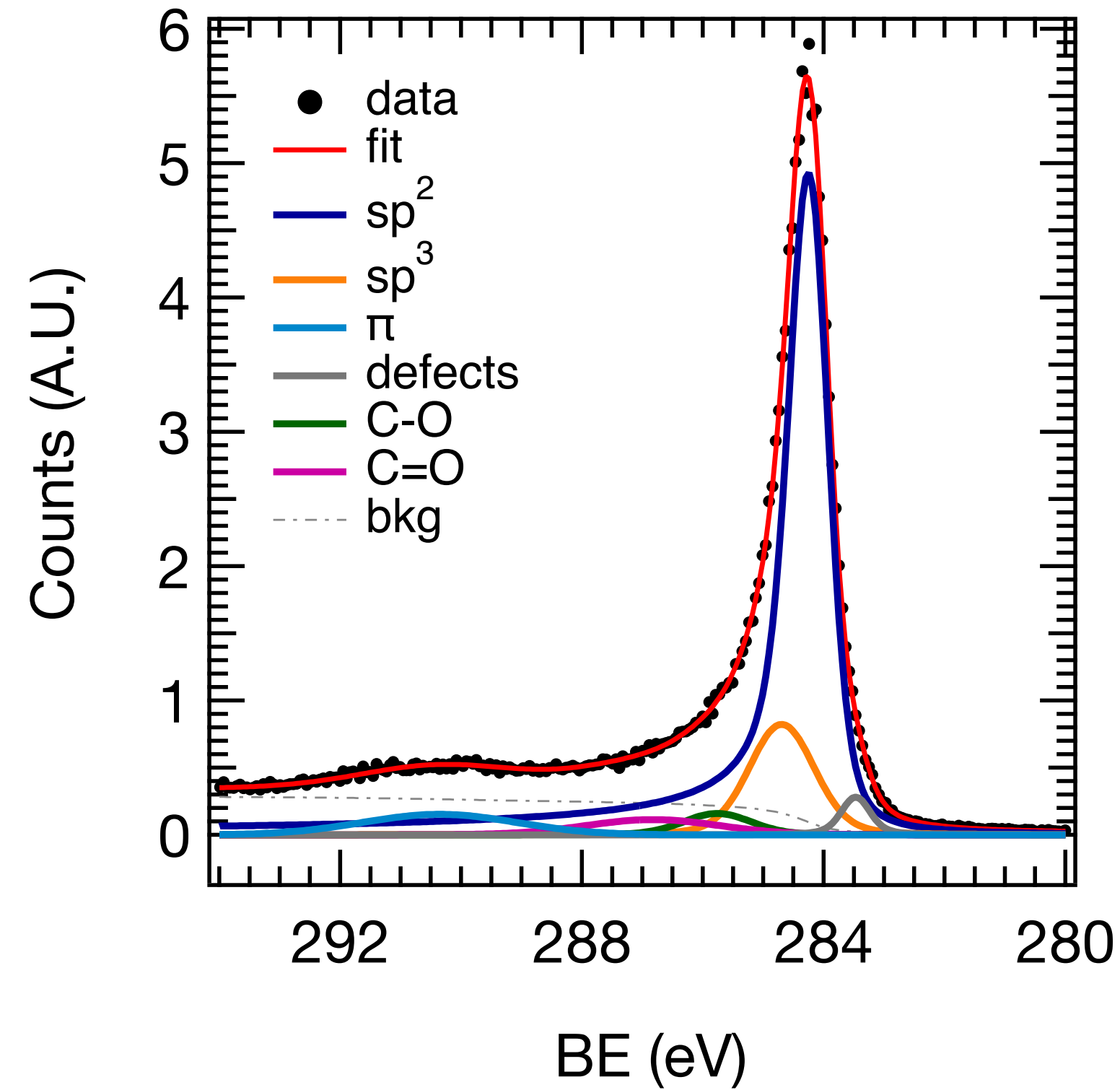
What about the uncertainty?

the **SE onset** strongly depends on how the data points for the fit are selected

choosing different “windows” of data points in the linear rising region $\pm \mathbf{0.05 \text{ eV}}$ should be a reasonable value







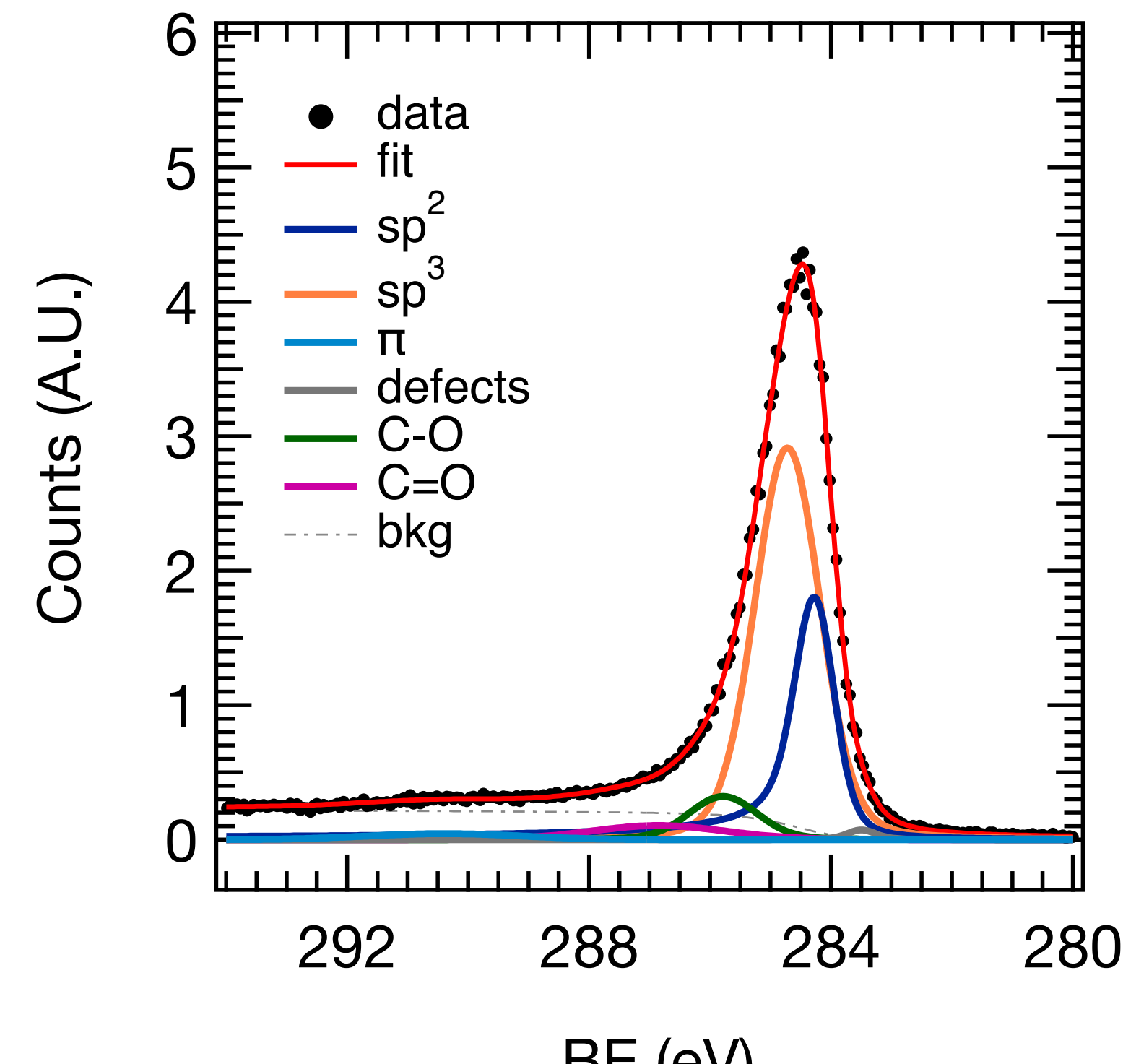
CNT_clean 8.64 ± 0.02

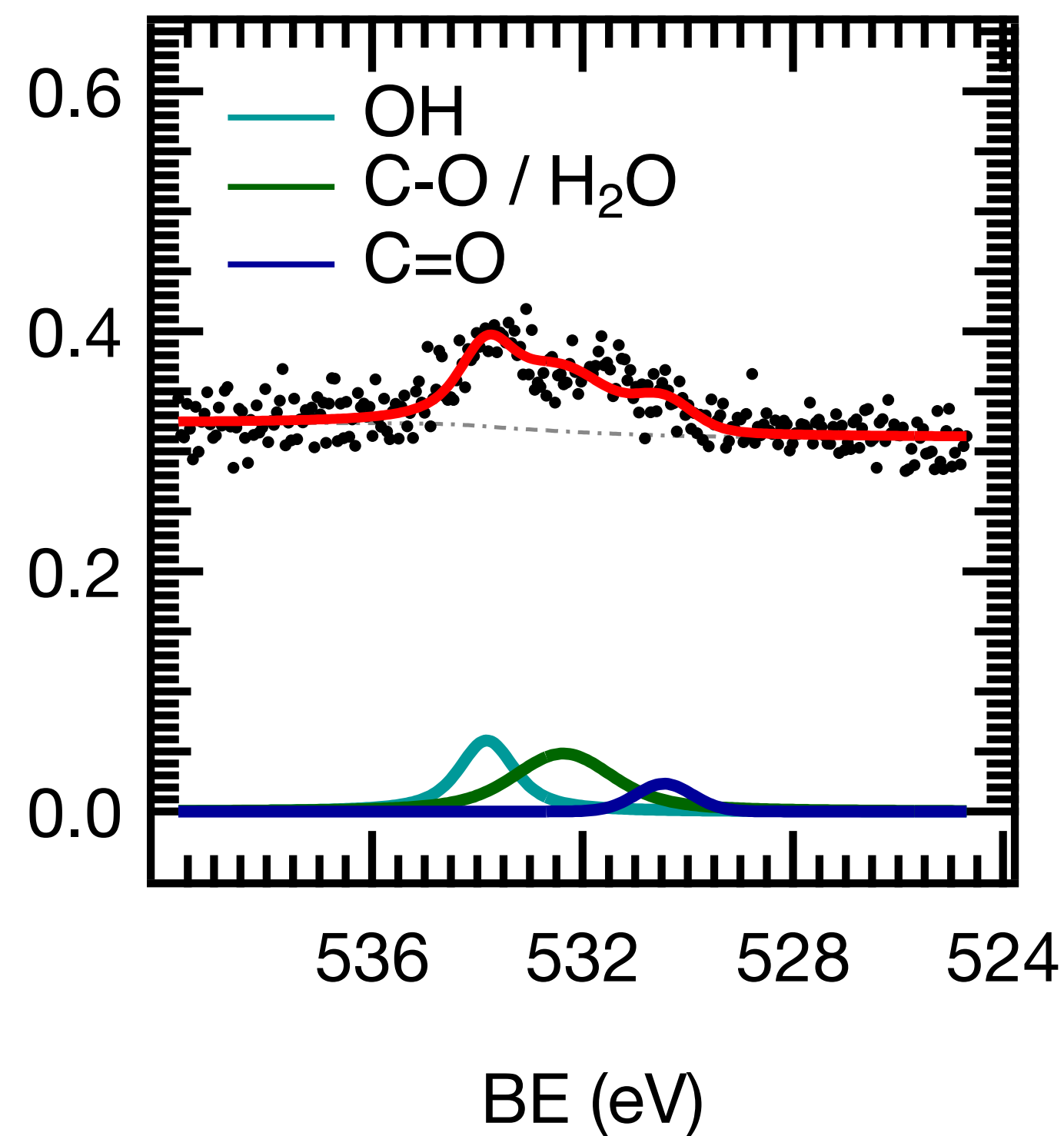
Asymmetry	Amp	Ek (eV)	GW	LW
0.100	5.73 ± 0.18	284.38 ± 0.02	0.62 ± 0.01	0.23 ± 0.01
0.00	1.19 ± 0.21	-0.48 ± 0.04	1.15 ± 0.06	
0.00	0.49 ± 0.23	-6.14 ± 0.07	3.00 ± 1.00	
0.00	0.20 ± 0.03	0.74 ± 0.03	0.44 ± 0.07	
0.00	0.24 ± 0.14	-1.55 ± 0.20	1.21 ± 0.27	
0.00	0.32 ± 0.16	-2.62 ± 0.55	2.50 ± 0.75	

CNT_H 7.48 ± 0.02

Asymmetry	Amp	Ek (eV)	GW	LW
0.100	2.09 ± 0.23	284.27 ± 0.02	0.62 ± 0.01	0.23 ± 0.01
0.00	4.20 ± 0.33	-0.48 ± 0.04	1.15 ± 0.06	
0.00	0.14 ± 0.07	-6.14 ± 0.07	3.00 ± 1.00	
0.00	0.05 ± 0.03	0.74 ± 0.03	0.44 ± 0.07	
0.00	0.48 ± 0.25	-1.55 ± 0.20	1.21 ± 0.27	
0.00	0.30 ± 0.16	-2.62 ± 0.55	2.50 ± 0.75	

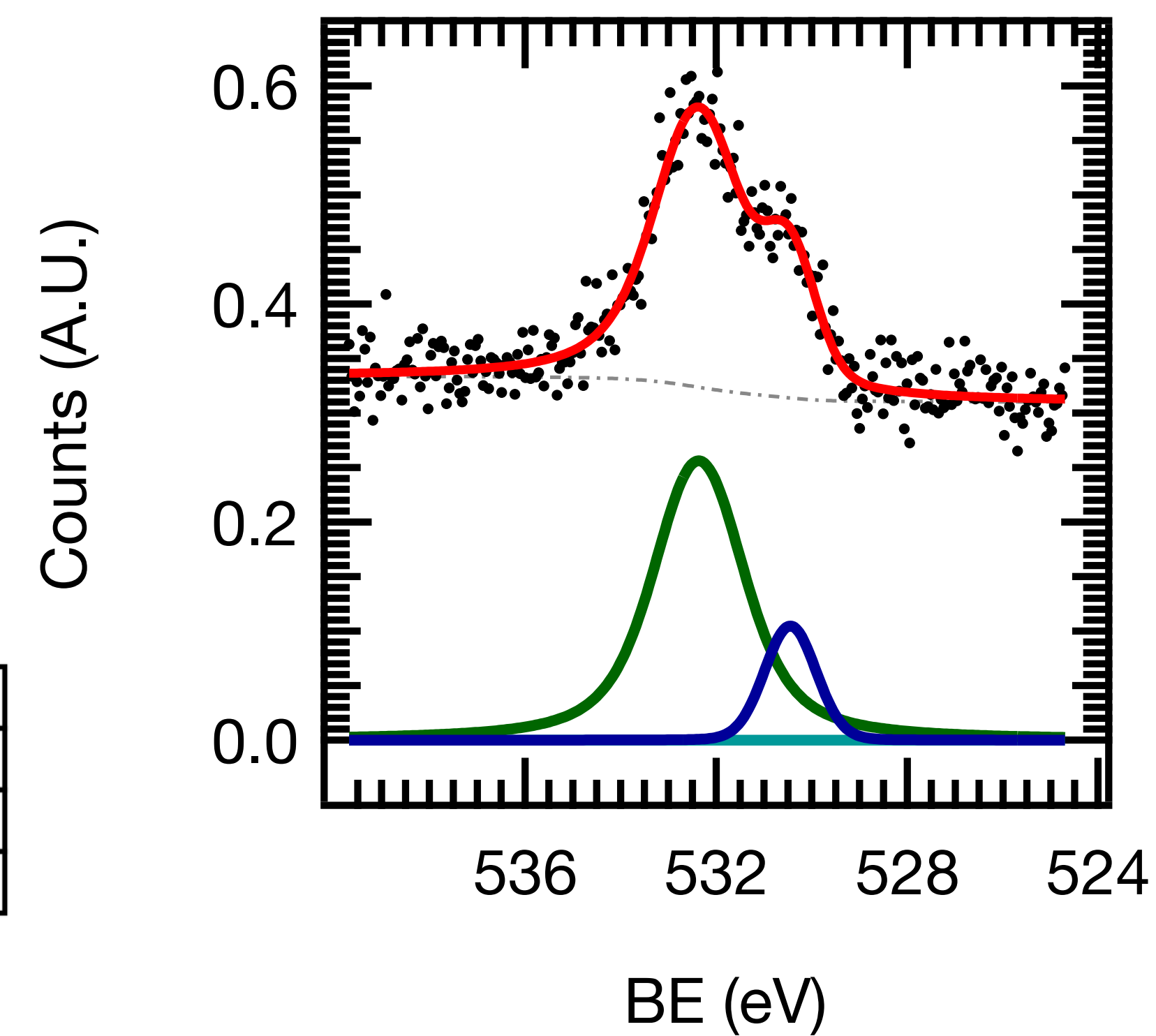
0.28
0.56
0.02
0.01
0.06
0.04

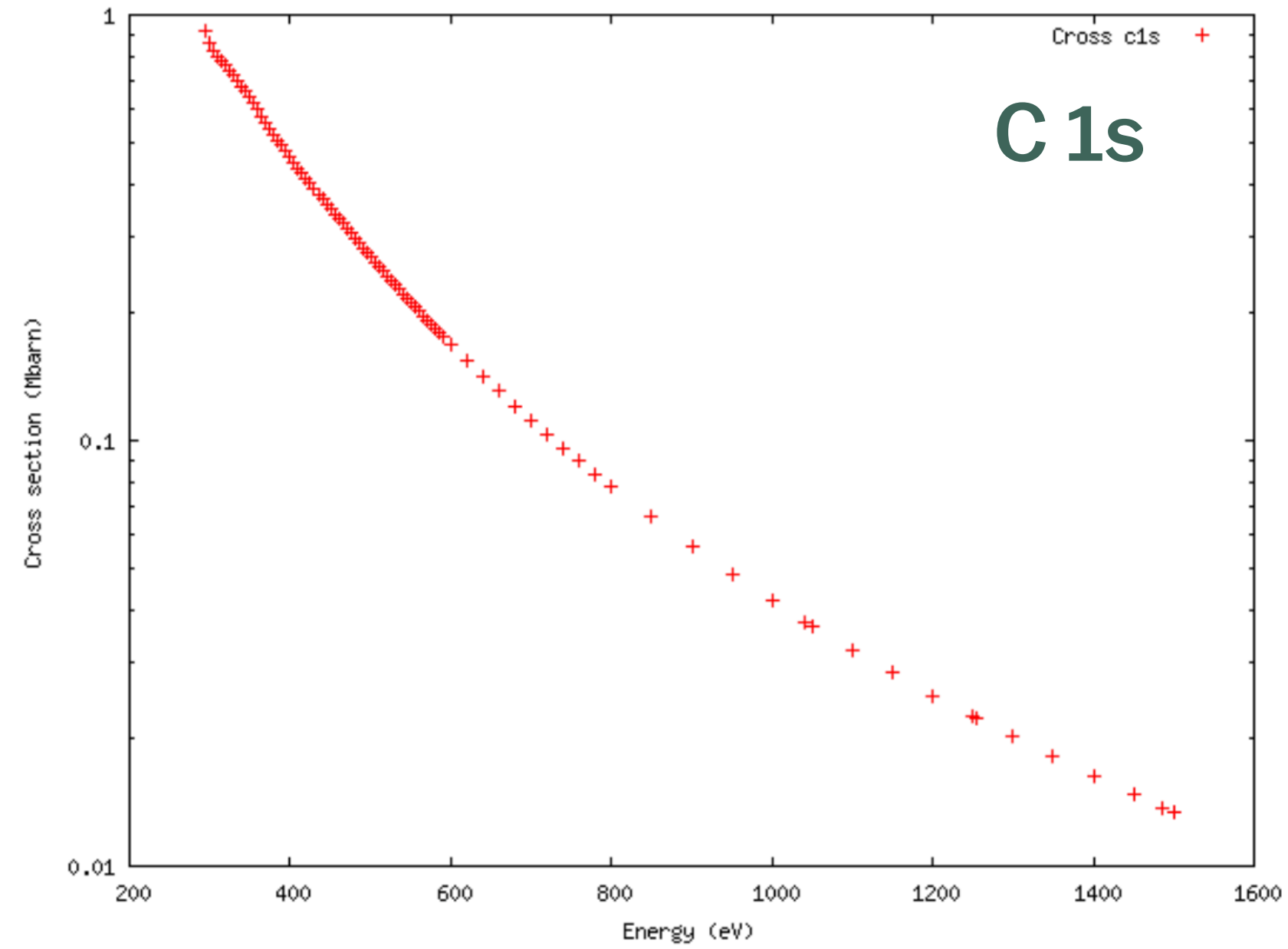




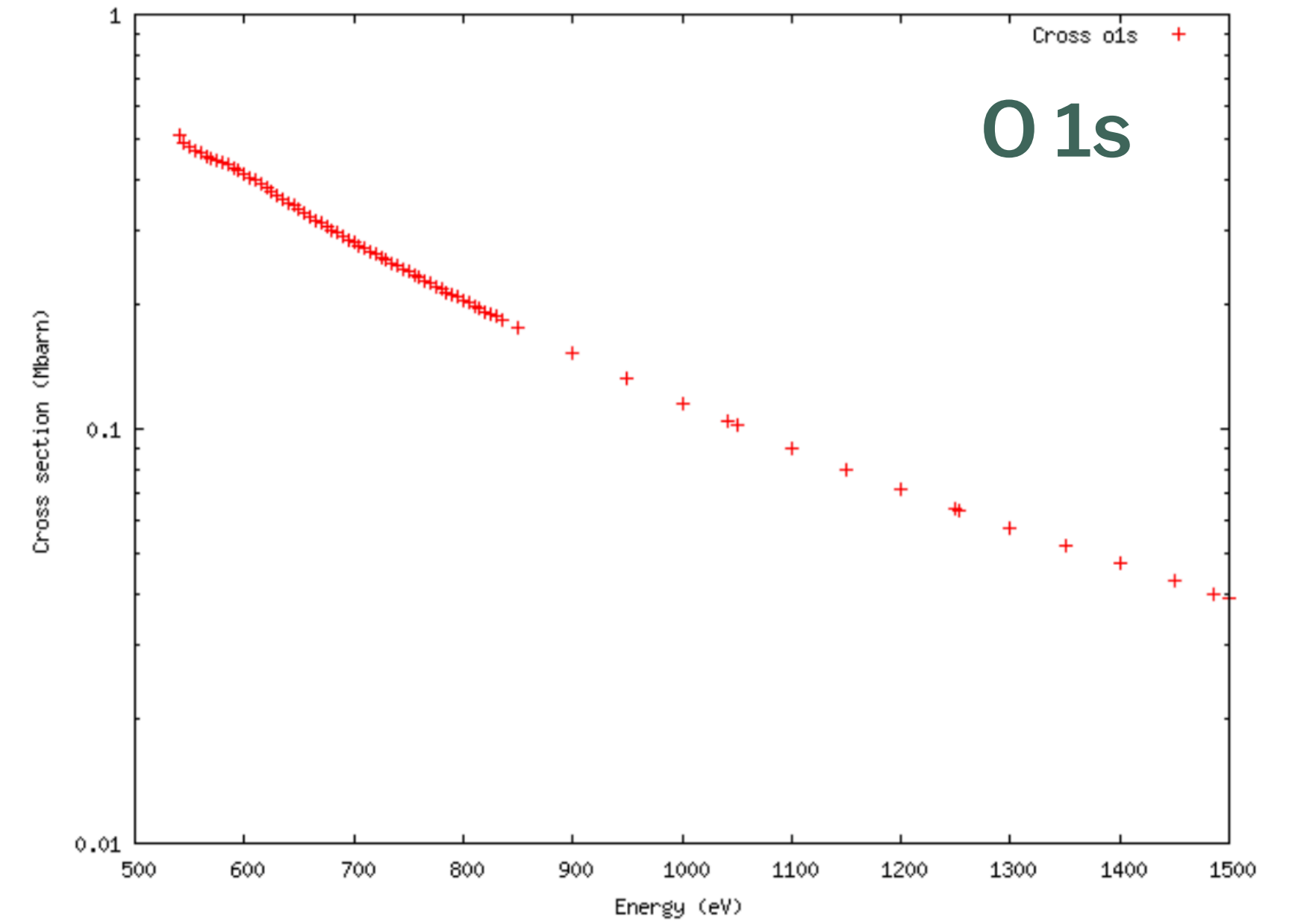
Asymmetry	Amp	Ek (eV)	GW	LW
0.00	0.10 ± 0.03	0.00	0.00	0.00
0.00	0.13 ± 0.03	0.00	0.00	0.00
0.00	0.03 ± 0.01	0.00	0.00	0.00

Asymmetry	Amp	Ek (eV)	GW	LW
0.00	0.00 ± 0.04	948.38 ± 0.07	0.65 ± 0.84	0.92 ± 0.82
0.00	0.71 ± 0.10	949.83 ± 0.05	1.51 ± 0.38	1.22 ± 0.47
0.00	0.14 ± 0.05	951.75 ± 0.08	1.23 ± 0.41	0.08 ± 0.71

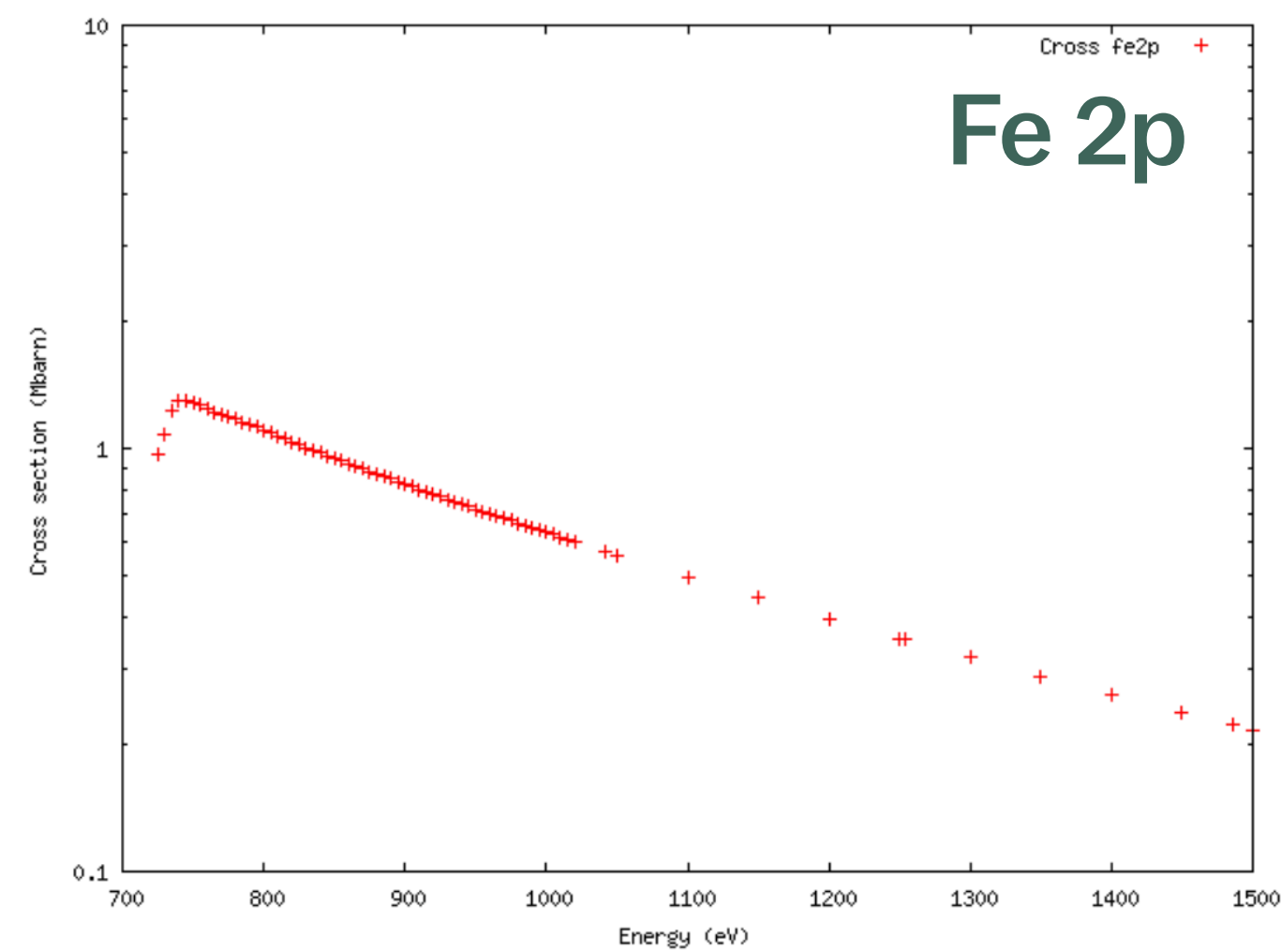




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